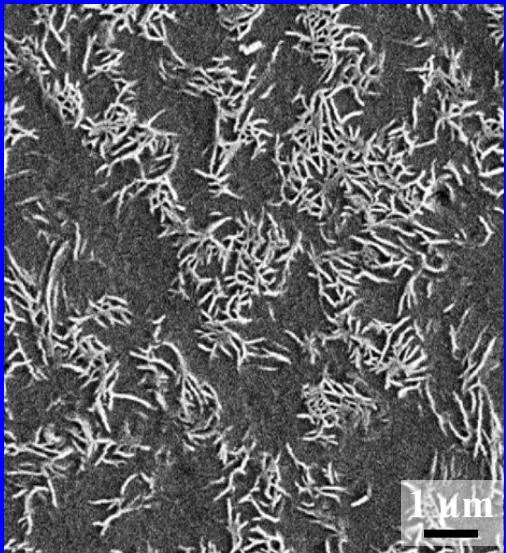
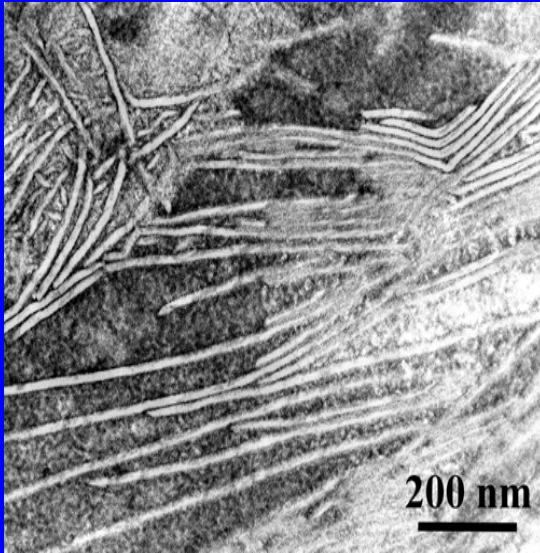
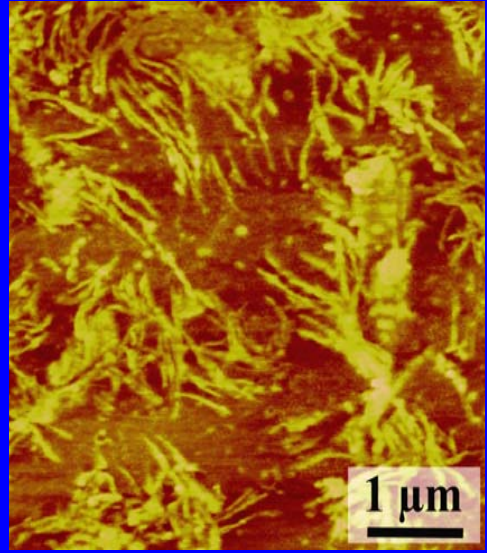
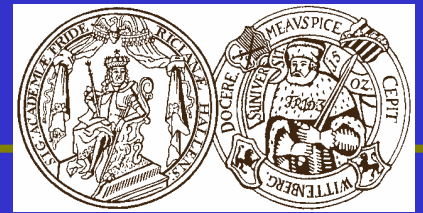


Morphological Investigations - Different Microscopic Techniques (Semicrystalline Polymers)

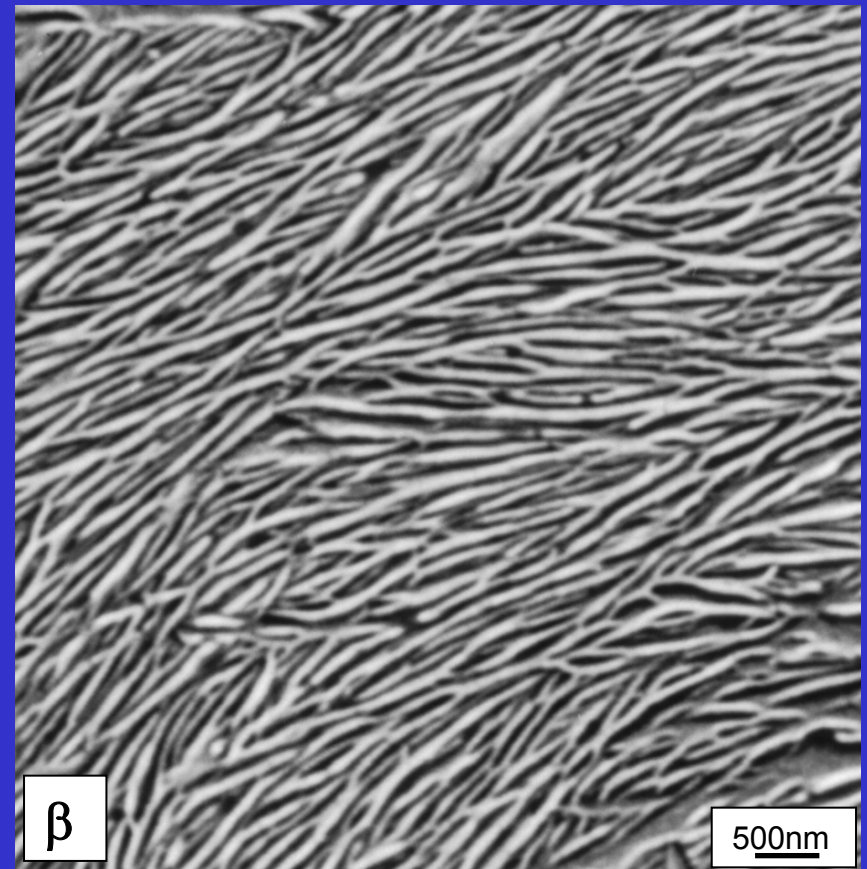
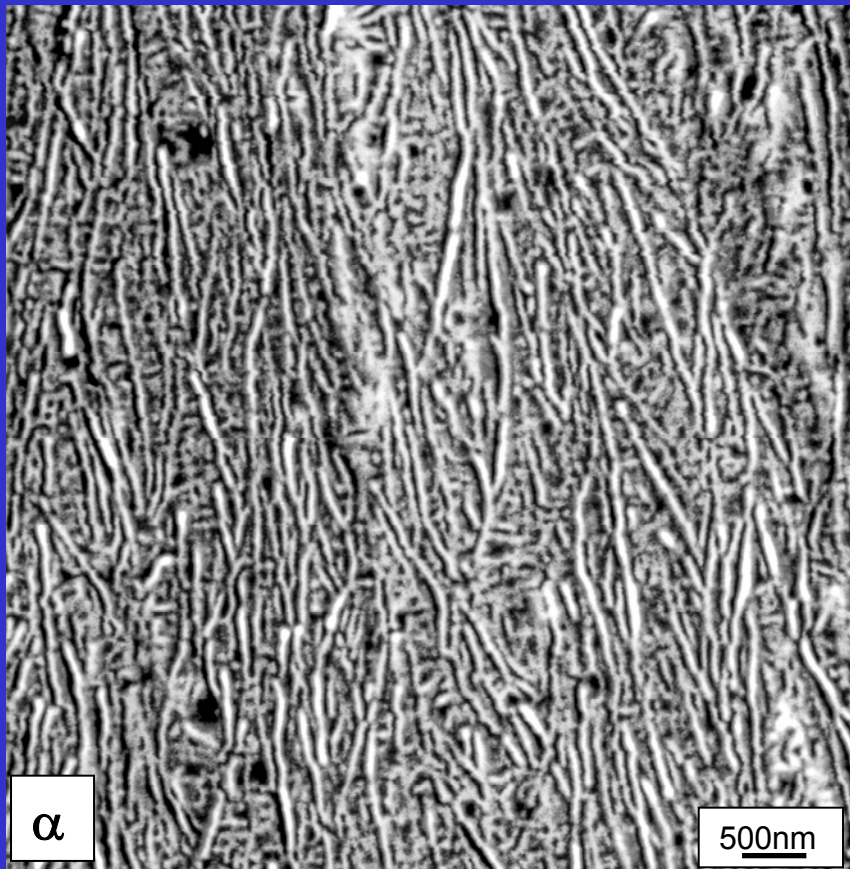
Method	SEM	TEM	AFM
<i>Typical Sample Preparation</i>	Evaporation Surface Etching	Ultramicrotomy Selective Staining	no special, but very flat surfaces are necessary
<i>Typical Results</i> <i>HDPE/EOC blends</i>			



Results

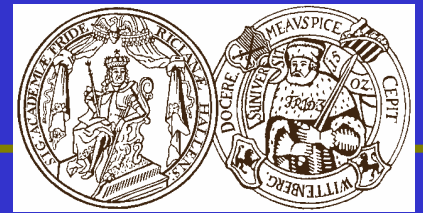


Morphology: SEM

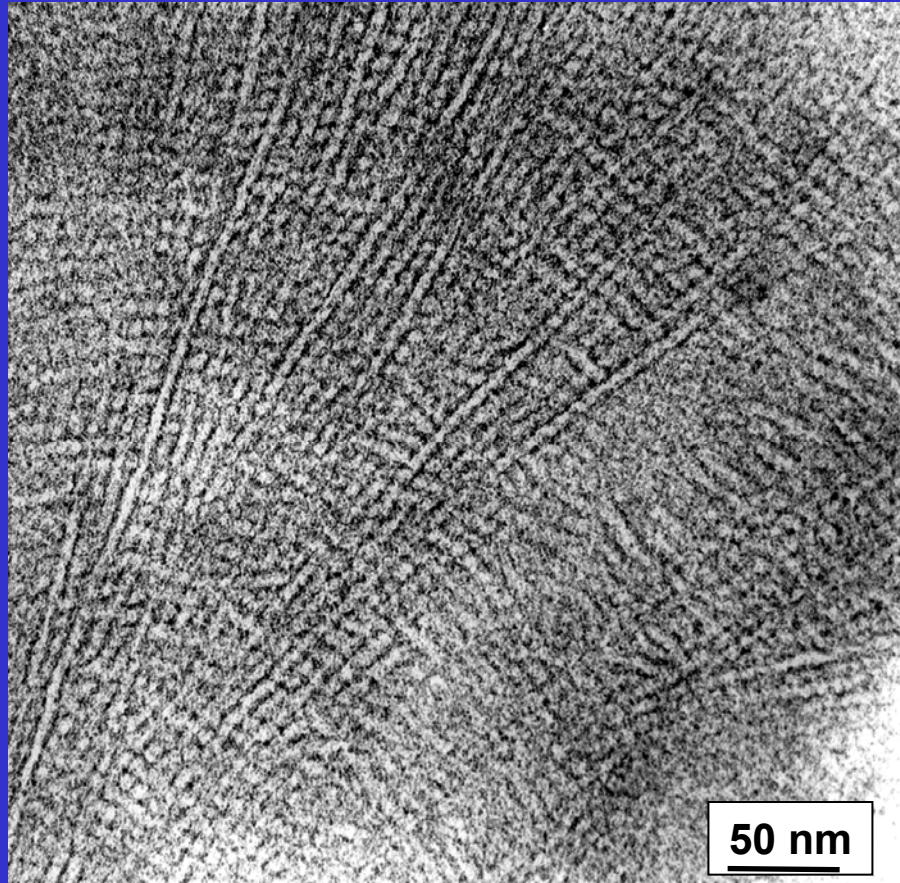




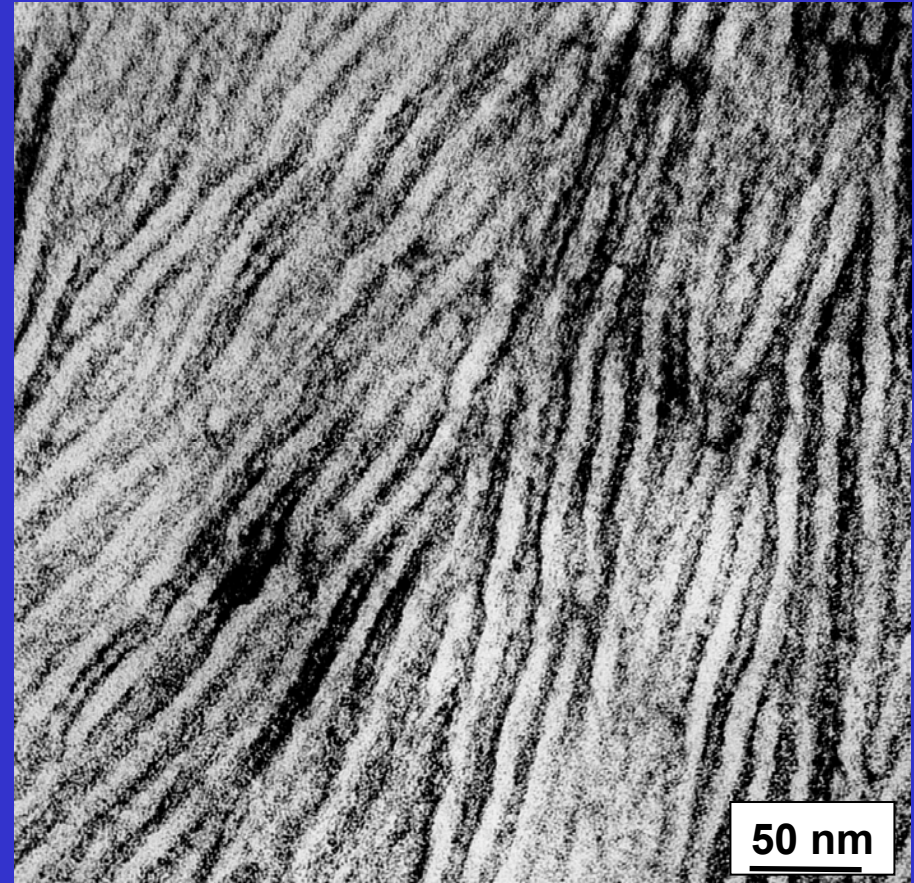
Results



Morphology: TEM



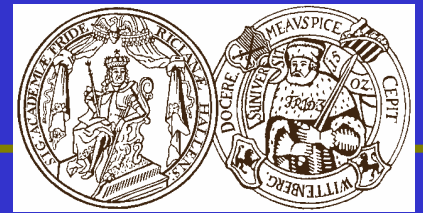
α



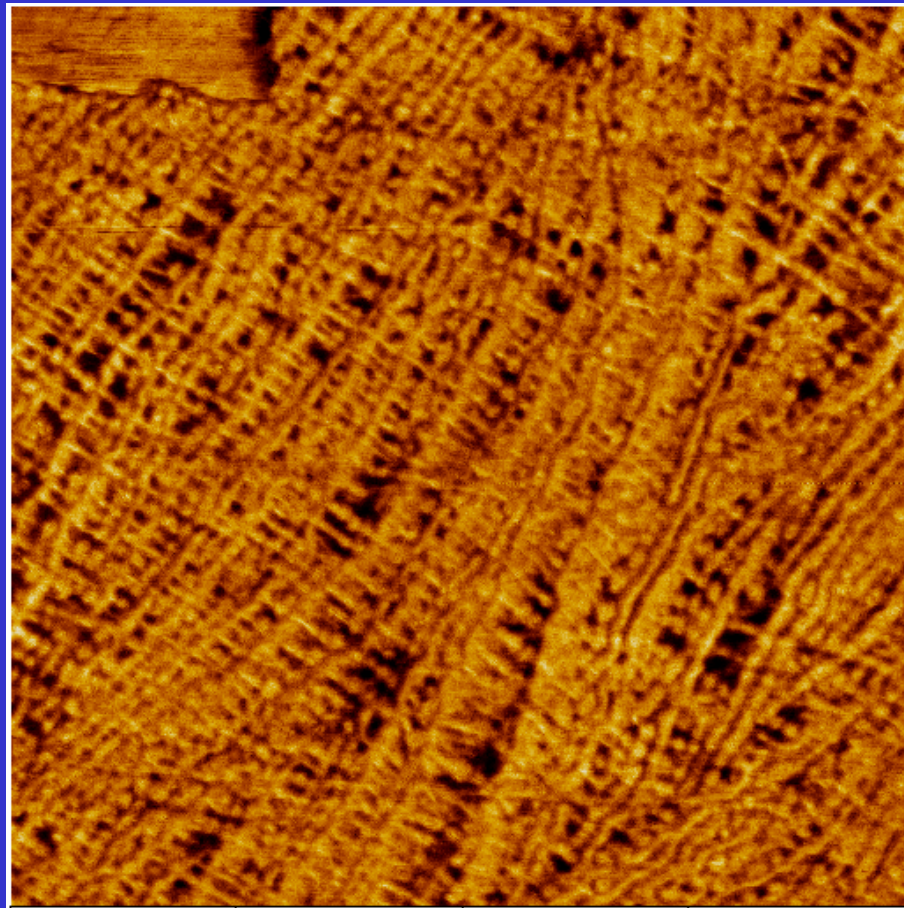
β



Results

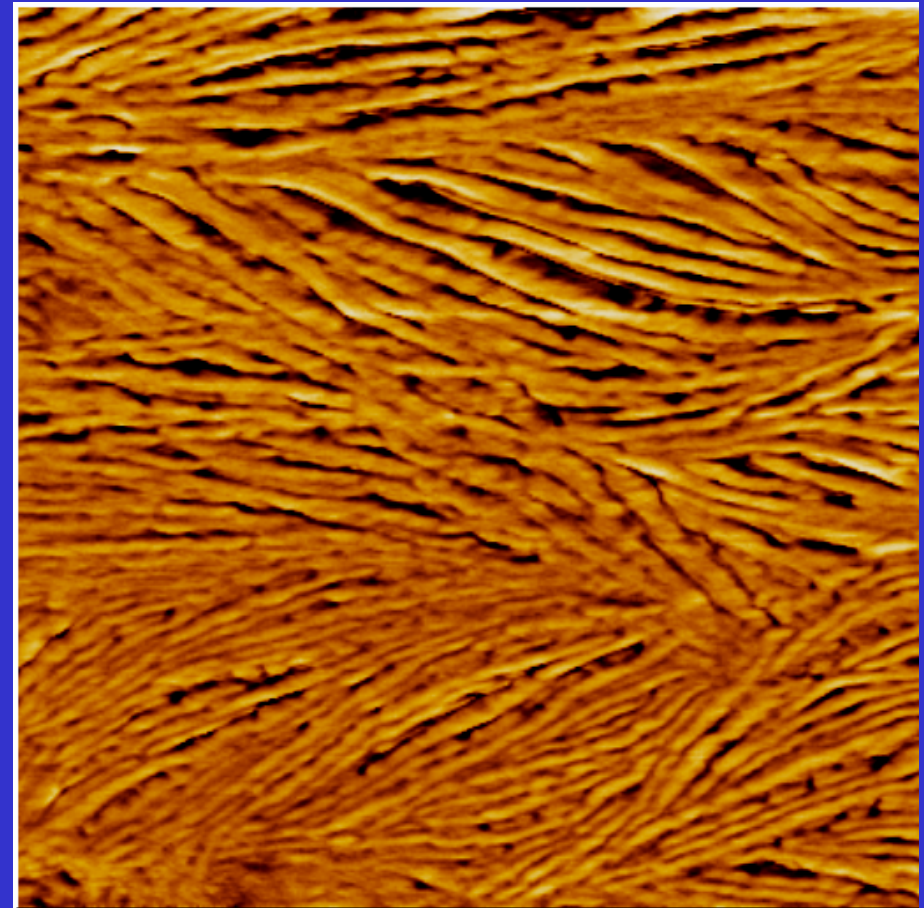


Morphology: AFM



α

1 μm



β

1 μm

II. Sample Preparation

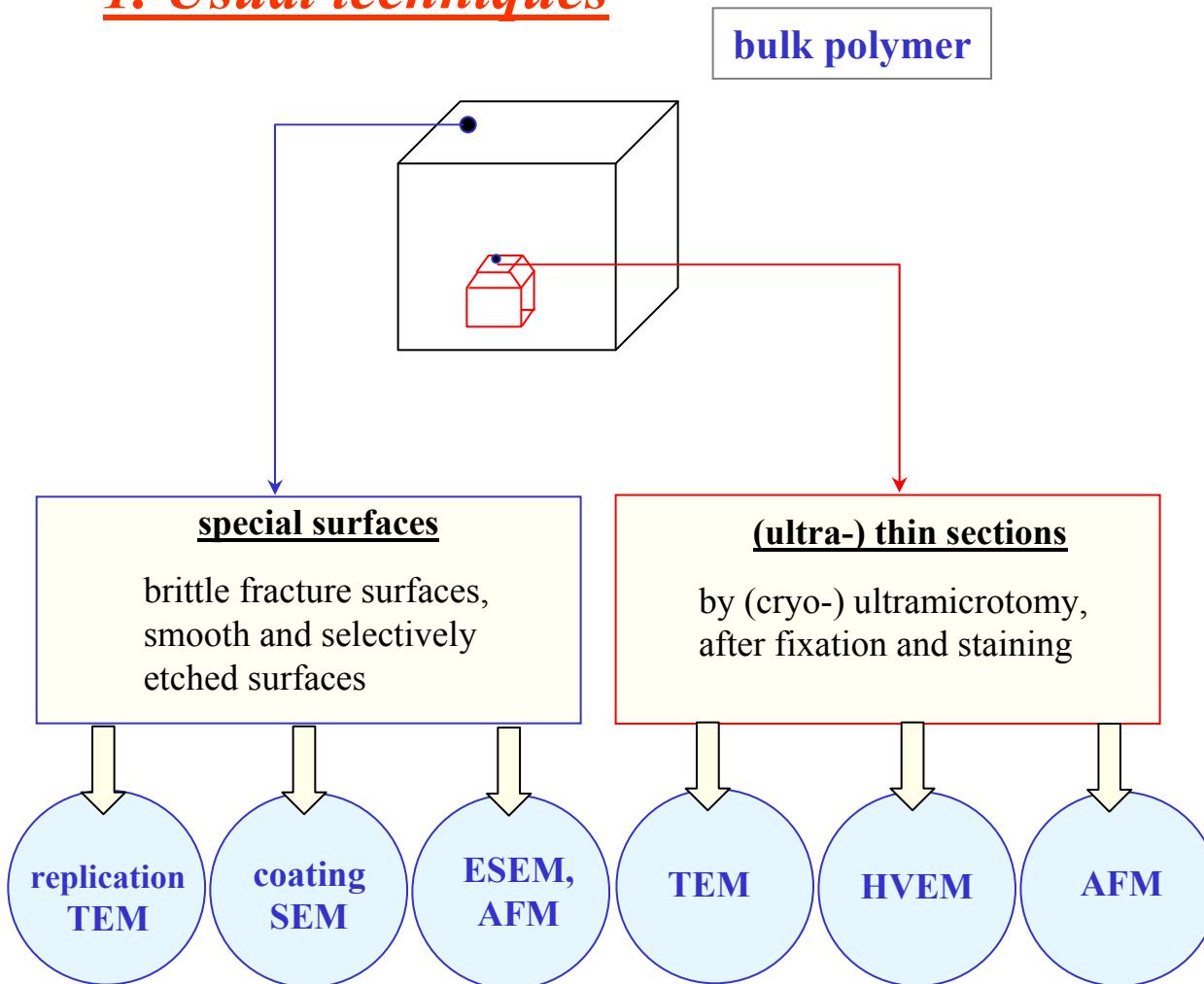
Surfaces

Cryo – Ultramicrotomy

Fixation and Staining of Polymers

EM investigation of morphology

1. Usual techniques



2. Special techniques

• Irradiation effects

γ - or electron irradiation at
 $T \geq RT$

↪ fixation and contrast
enhancement

• Straining effects

Straining of (semi-) thin
sections

↪ contrast
enhancement

Bulk Polymeric Material

preparation of surfaces

surfaces of fibres,
foils; freely
crystallized from
melt or solution

polished or
sectioned surfaces
(by microtomy,
polishing)

fracture surfaces
(fracture at
low temperatures,...)

selective etching
(chemical, physical
etching)

“structured surfaces”

replica
(one-stage,
two-stage)

TEM

evaporating,
conductive
layer

SEM

SFM

preparation of thin sections

fixation, hardening:
chemical (cross-linking...)
physical (cooling, cross-linking...)
mechanical (embedding) effects

selective staining:
selective chemical reactions,
physical effects

(cryo-) ultramikrotomy

*ultra-thin
sections*

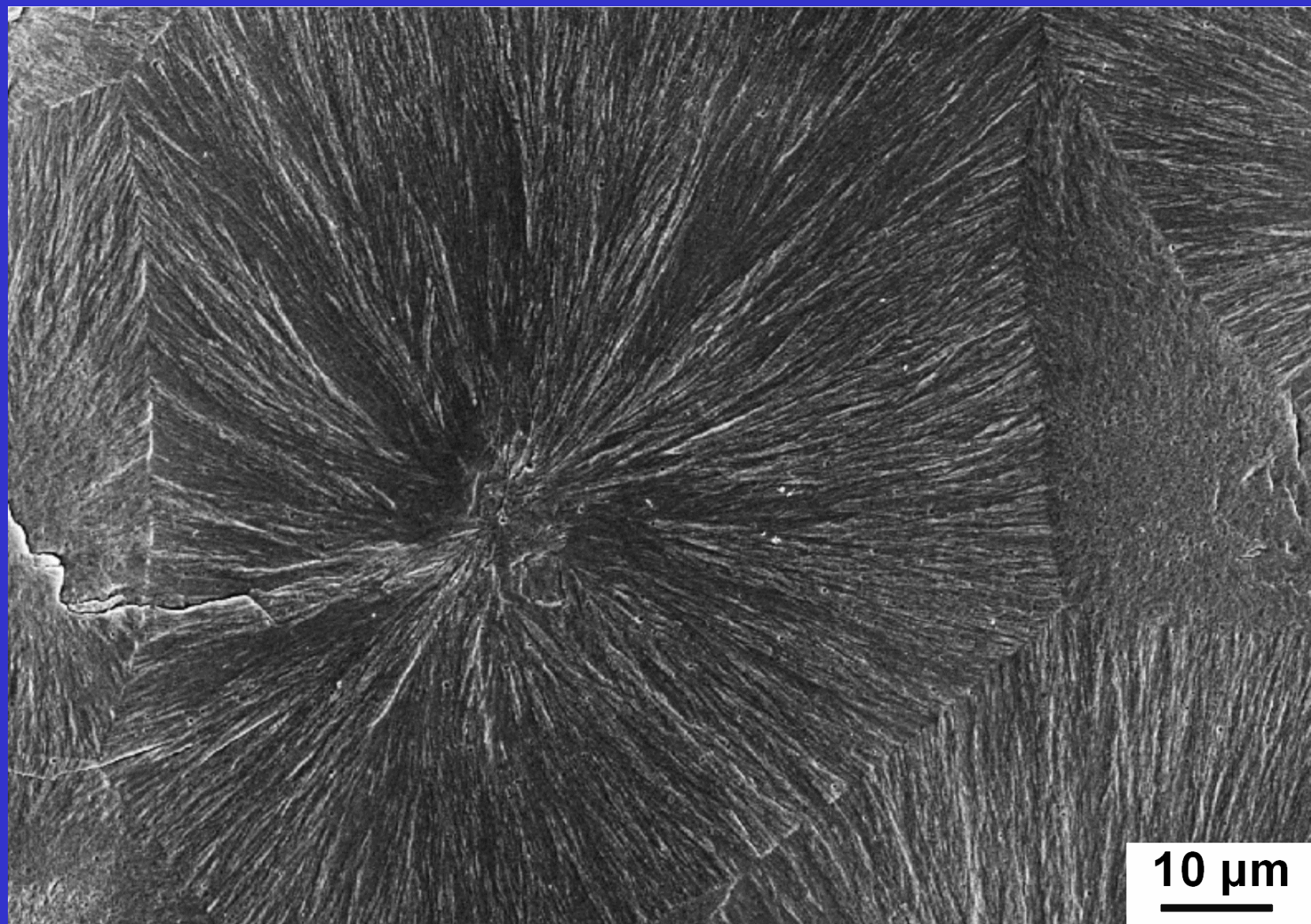
TEM

SFM

*semi-thin
sections*

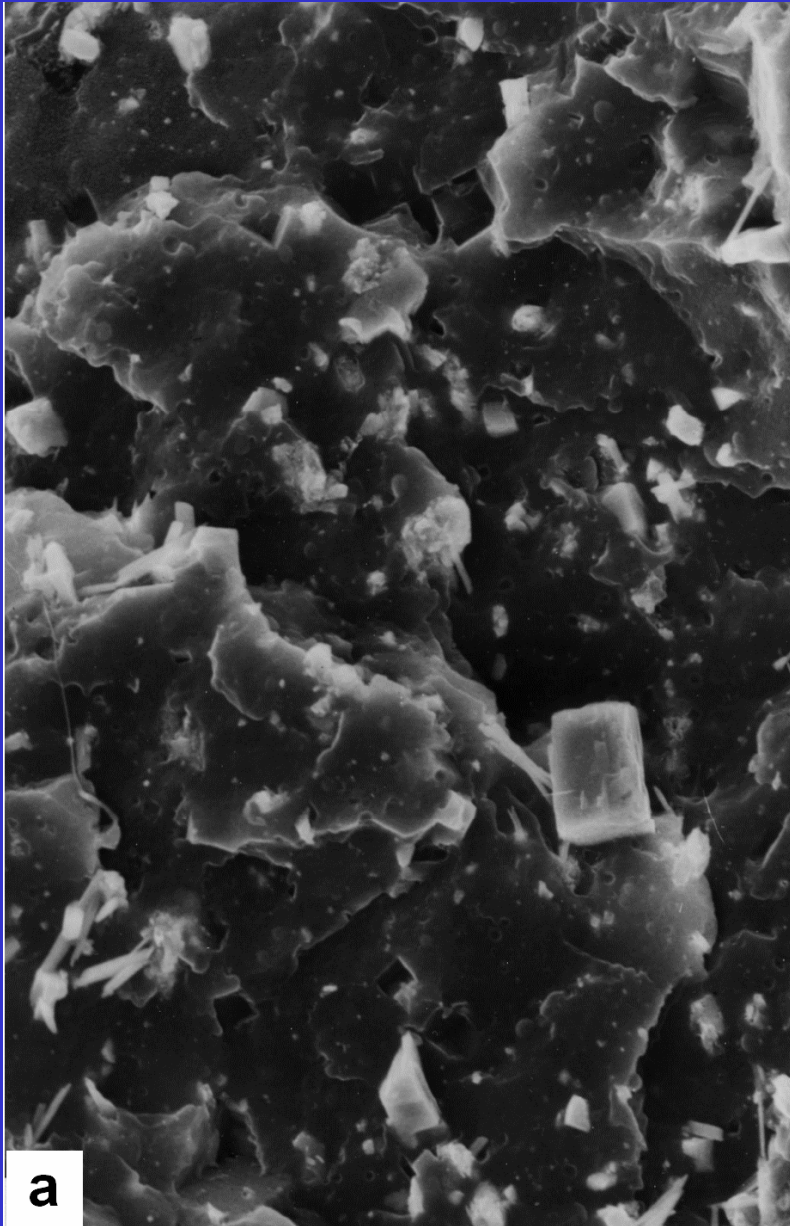
HVEM

Surface of α iPP after permanganic etching, SEM

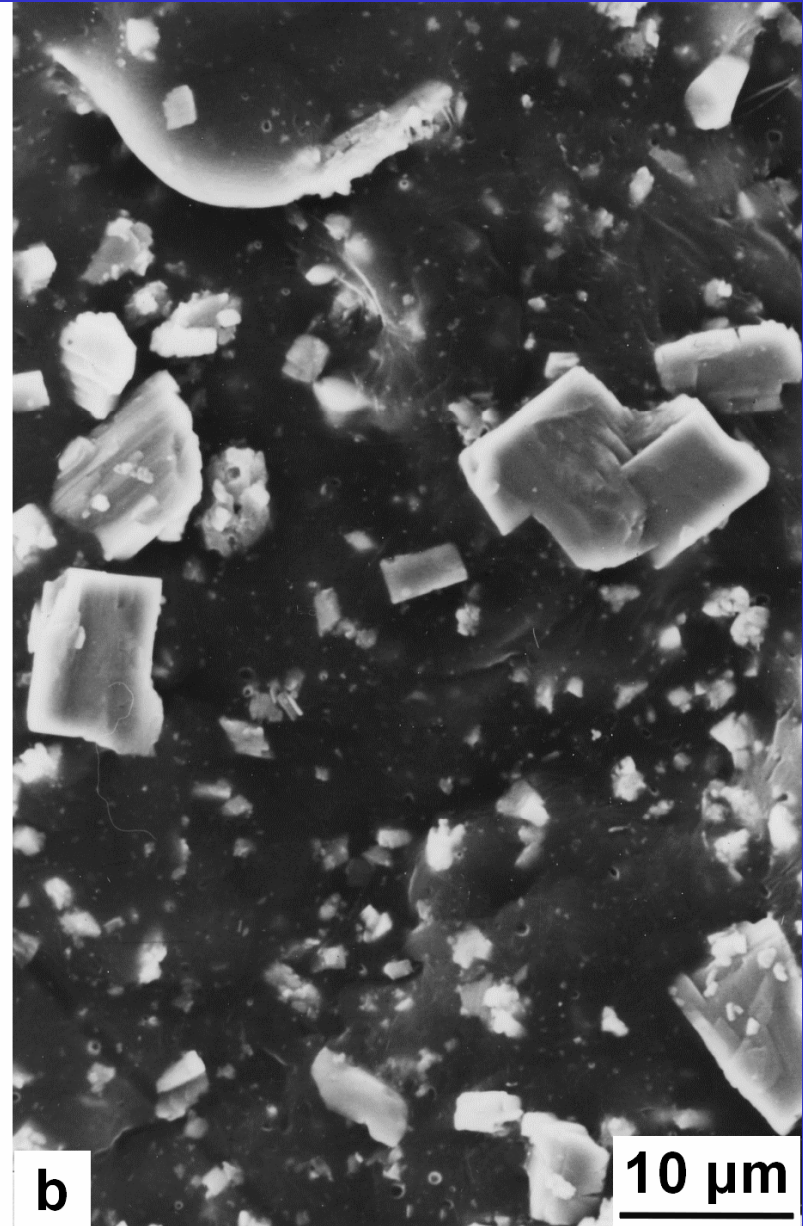


PP / CaSO₄ - Composite

Usual brittle fracture



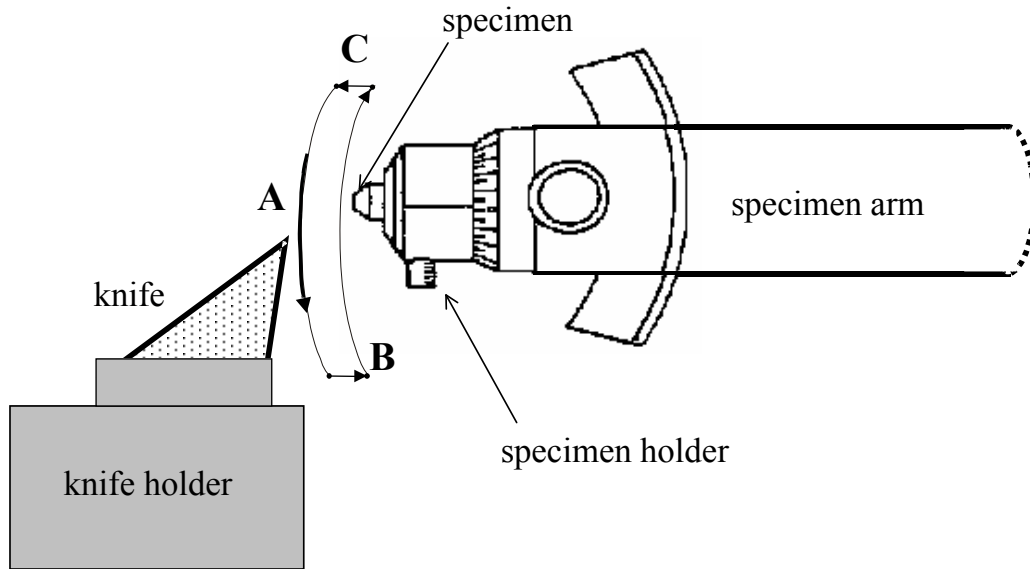
Soft matrix fracture



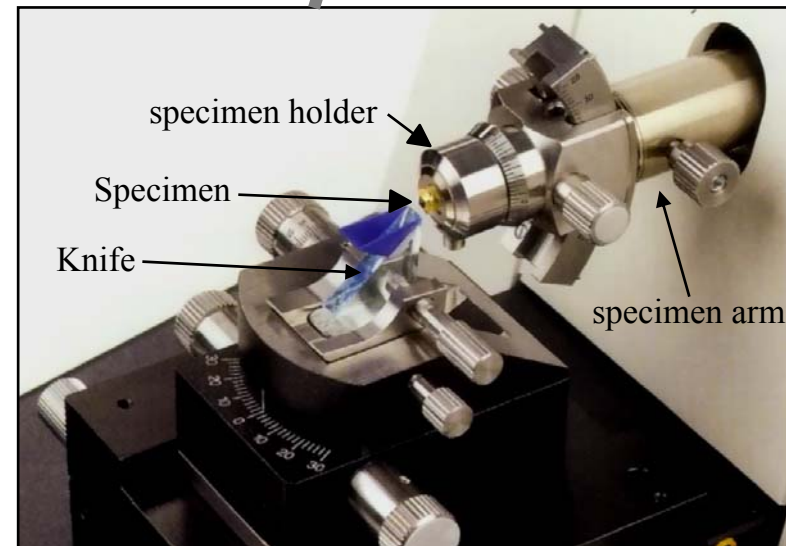
Cryo-Ultramicrotome UCT (Fa. Leica)



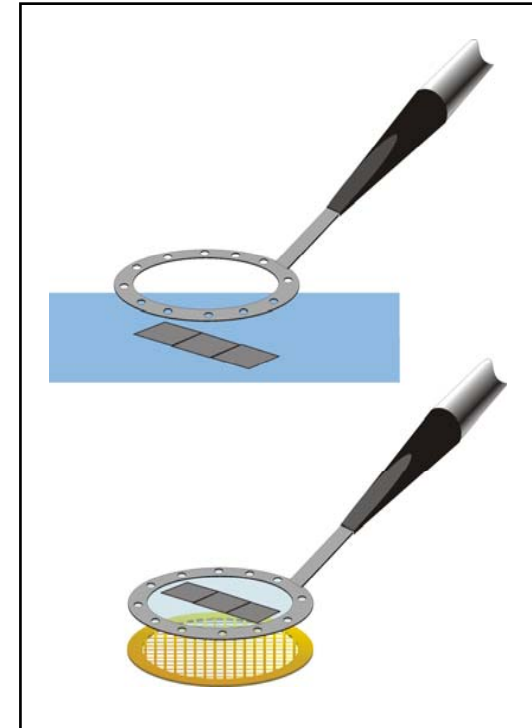
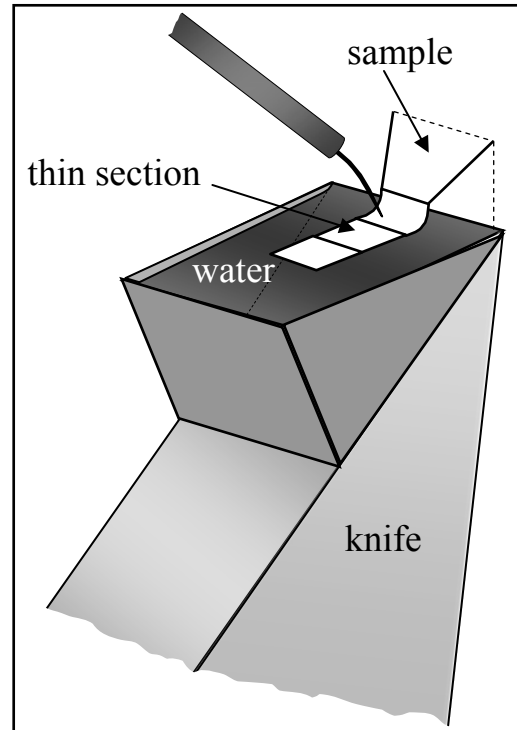
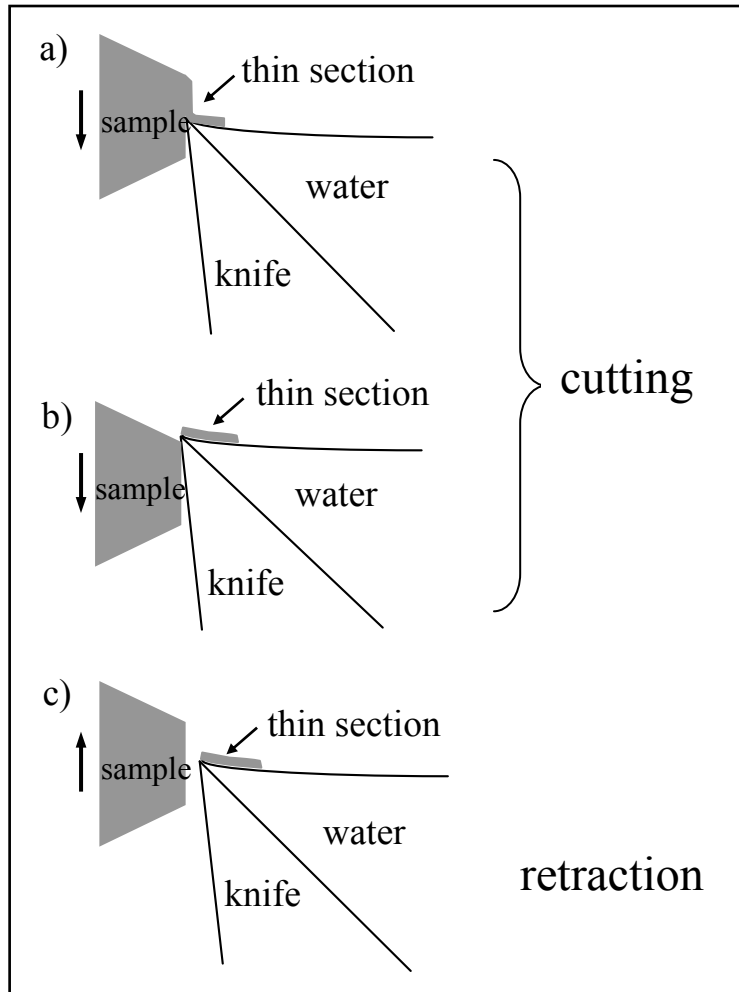
Principle



- A - specimen cut with controlled speed
- B - retraction
- C - advance of specimen arm determines the specimen thickness



Cutting



Important Staining Agents for Polymers

Polymer	Staining agent
Polyolefins	ClSA / OsO ₄
	RuO ₄
	ClSA / Uranyl acetate
Polyamide	Formalin / OsO ₄
	PTA / OsO ₄
	RuO ₄
Polyacrylate	Hydrazine / OsO ₄
	ClSA / OsO ₄
	RuO ₄
Polystyrol, Styrol copolymere	RuO ₄
	OsO ₄
Polyuretane	ClSA / OsO ₄
	RuO ₄
Polyvinylchlorid	ClSA / OsO ₄

OsO₄ - Osmium tetroxide
ClSA - Chlorosulfonic acid

RuO₄ - Ruthenium tetroxide
PTA - Phosphotungstic acid

Image - Processing

- Improvement of contrast
- Quantitative measuring of structural details

Image Processing - Optimization of gray value distribution

Lookup table

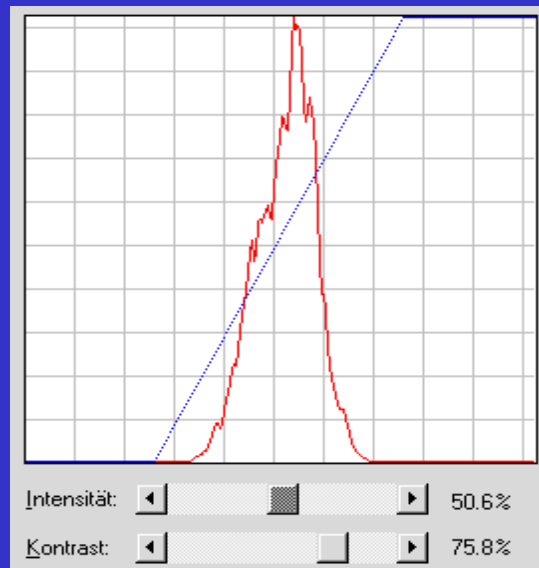
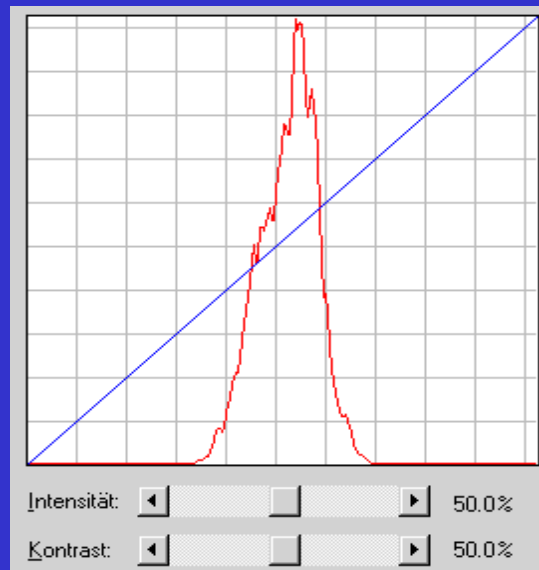
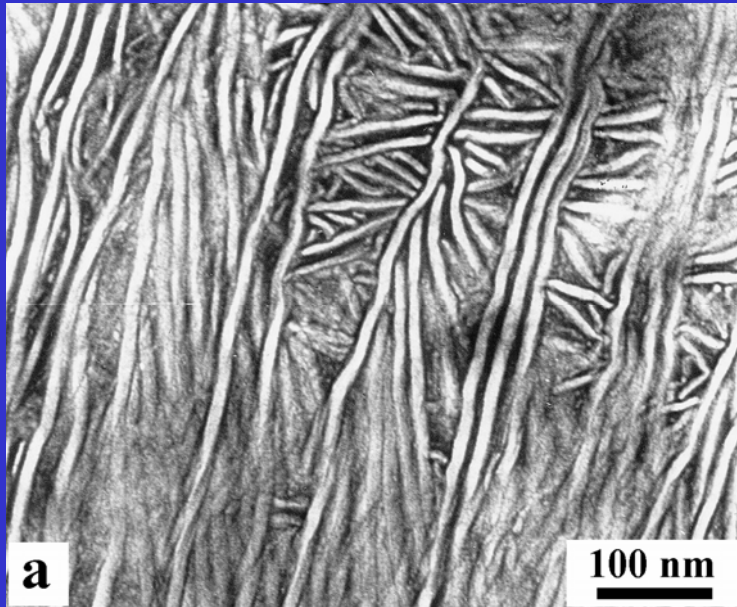
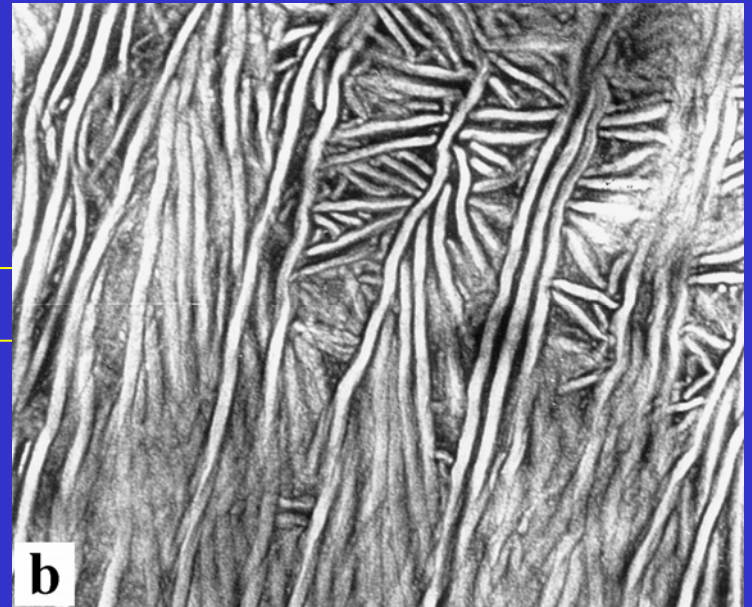


Image Processing - Filter Operation

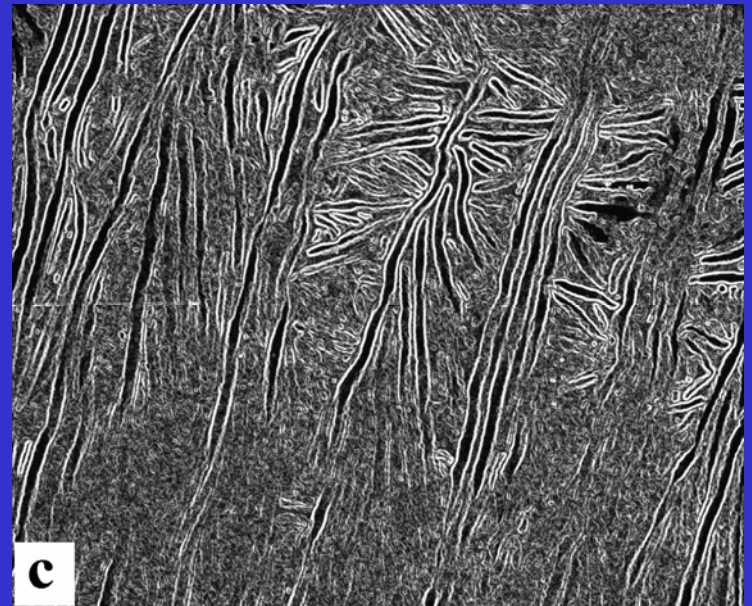
TEM micrograph of HDPE



→ Low pass



→ High pass



PE: Lamellae and laser-light diffraction pattern

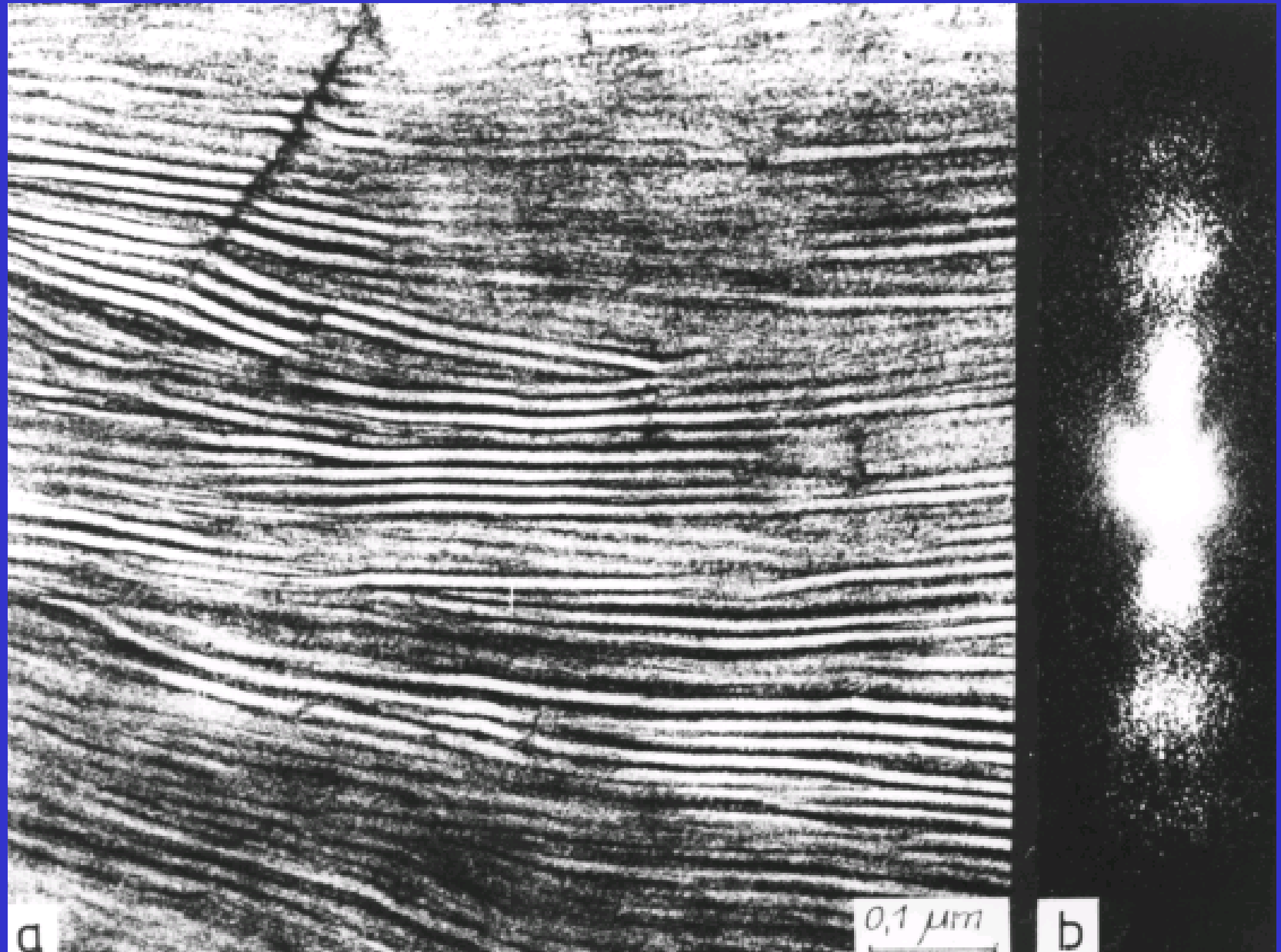
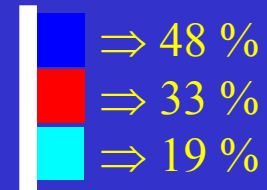
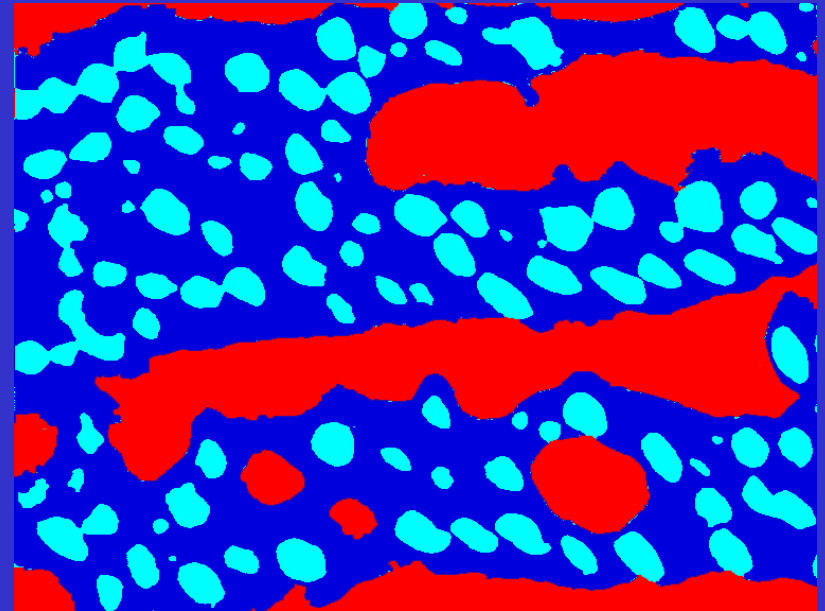
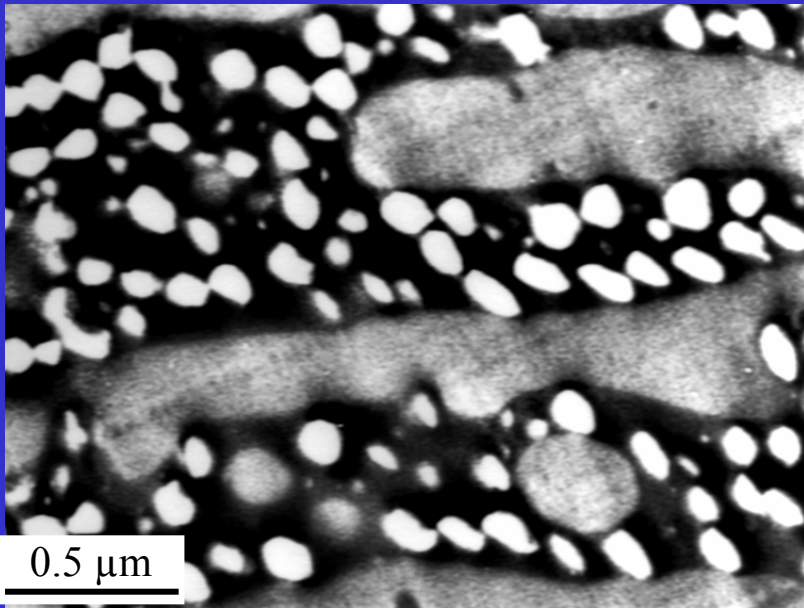


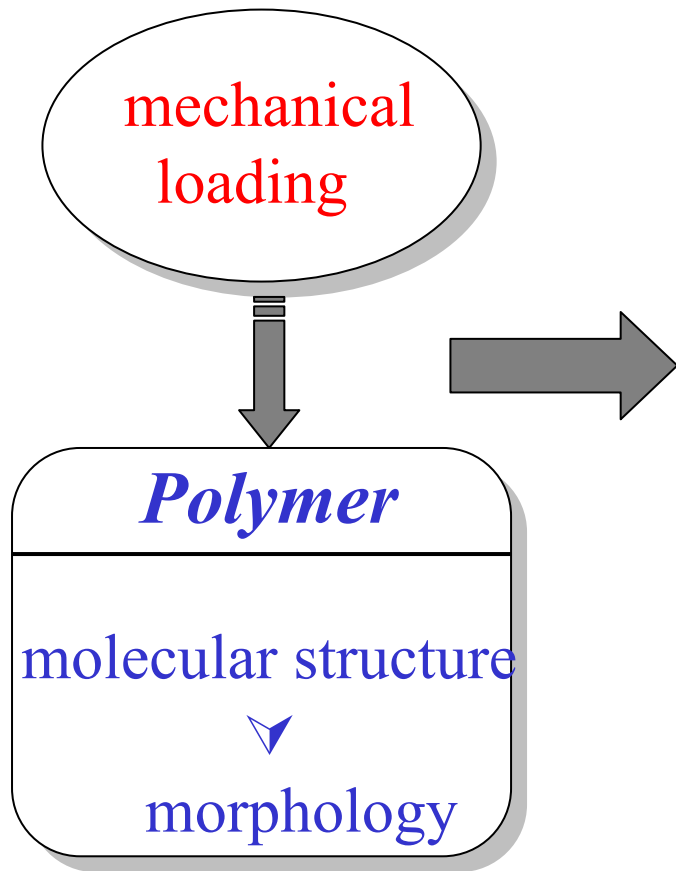
Image Processing - Phase Determination

TEM image of an ultra thin section



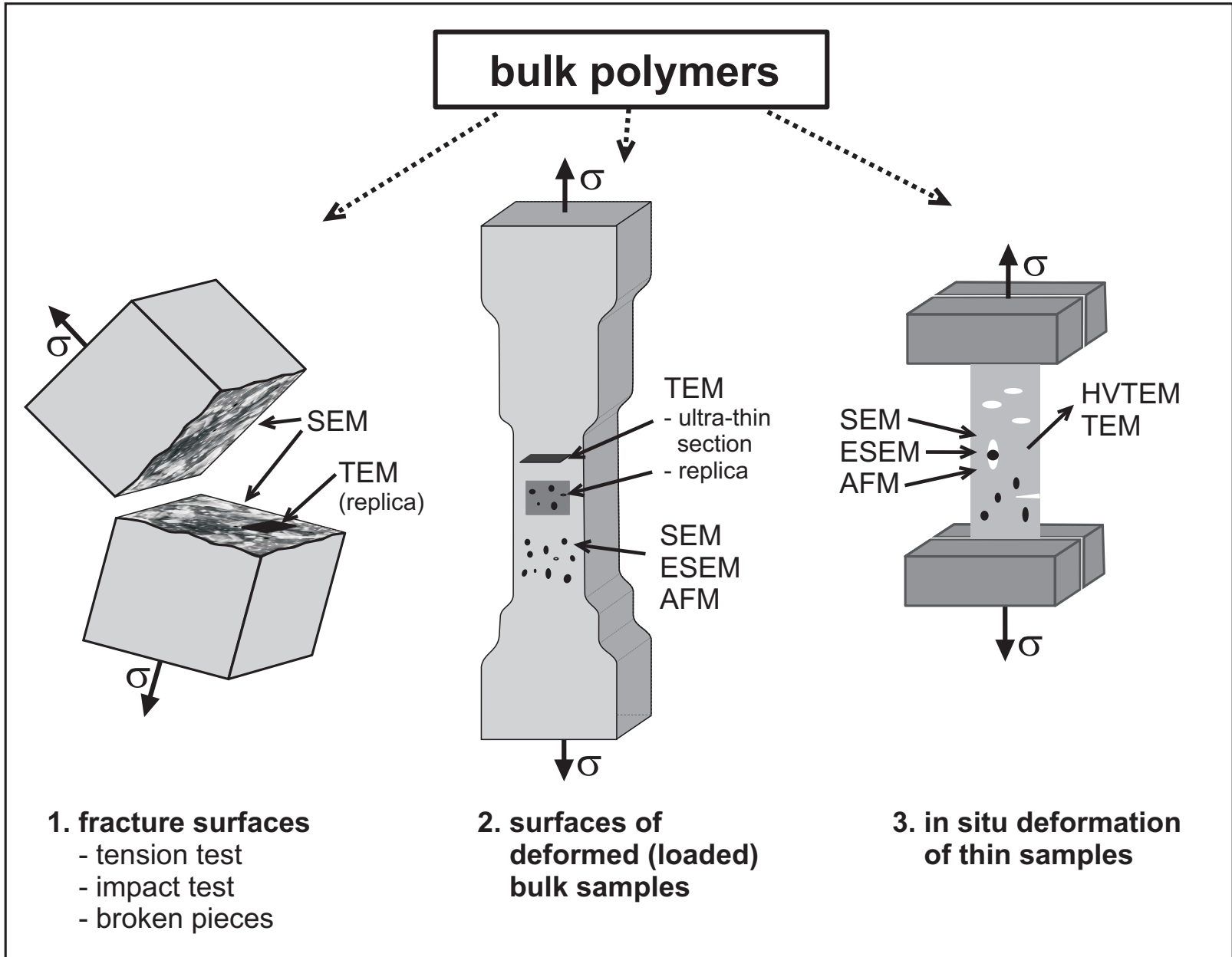
III. Micromechanical Testing of Polymer Properties

Micromechanical Mechanisms



<i>scale</i>	<i>processes</i>
↑ nm	stretching of chain segments, reptation movements, chain scission
μm	microvoid formation
μm	microyielding crazing shear band formation micro flow
mm ↓	crack initiation & propagation fracture

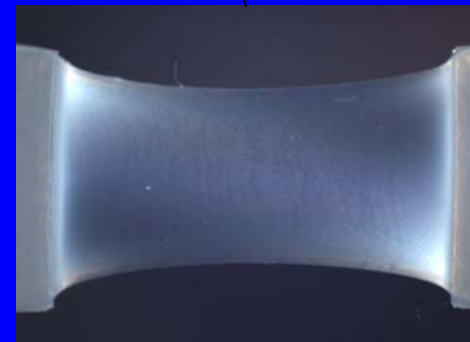
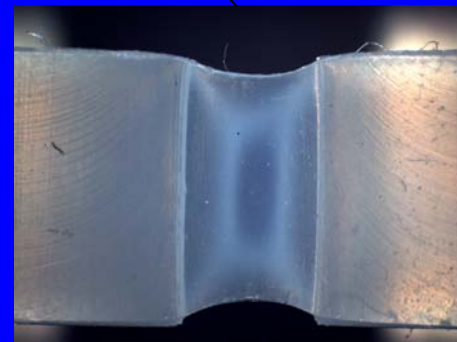
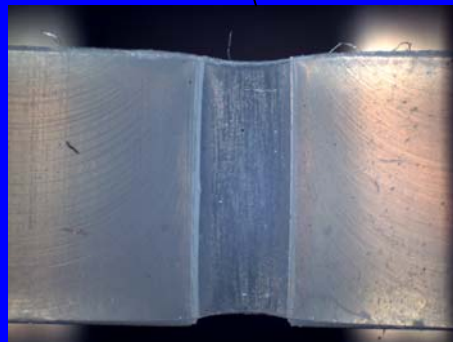
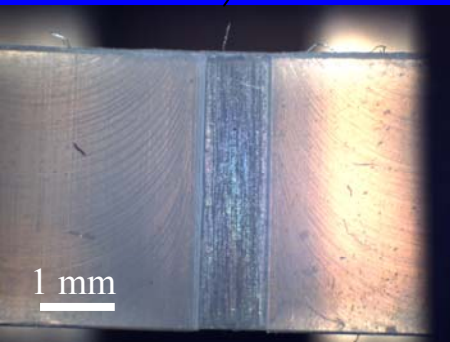
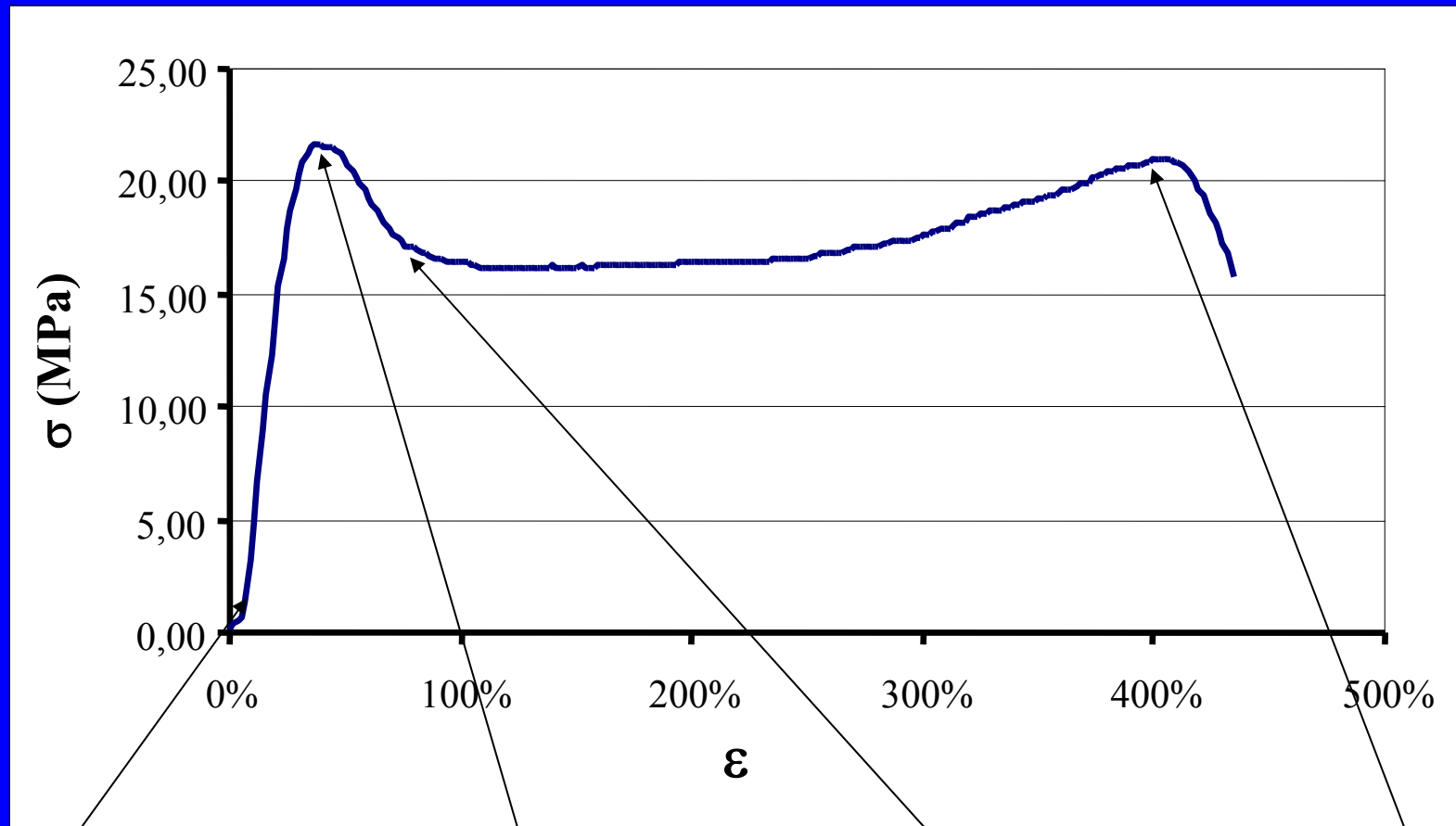
Investigation of micromechanical processes using EM



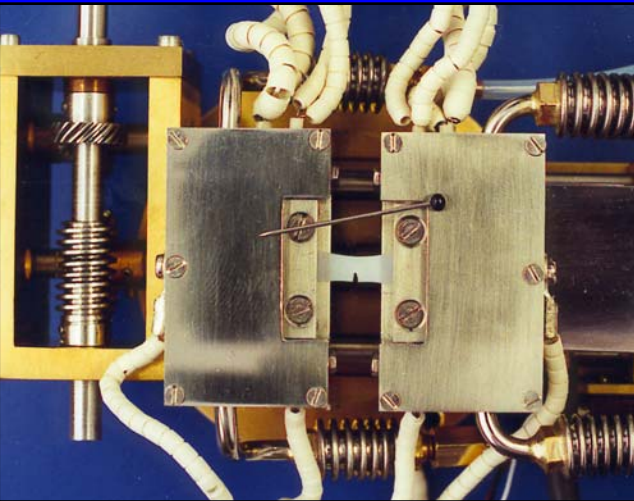
Tensile Test under Optical Microscope



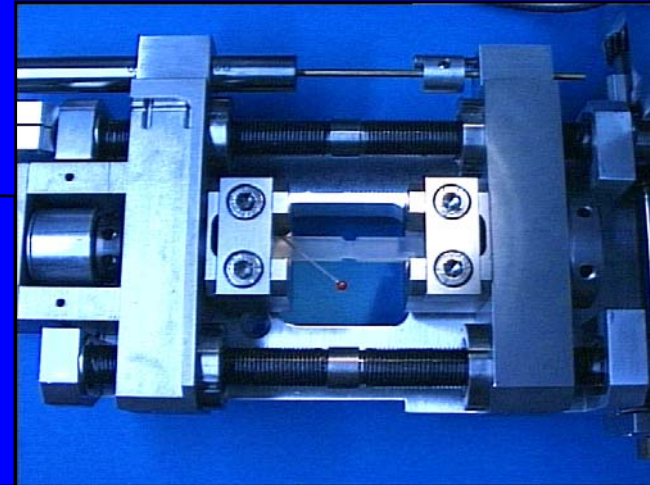
Tensile Test of HDPE using Miniaturised Specimens under Optical Microscope



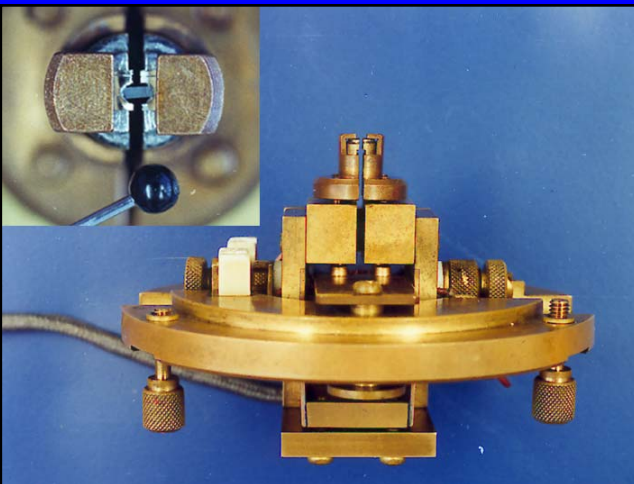
Tensile stages for micromechanical in situ investigations



Scanning Electron Microscope
Tensile Stage B156
(Oxford Instruments)
Temperature: -180 °C ... 200 °C
Thickness: 0.5 μ m ... 0.5 mm



**Scanning Electron Microscope and
Atomic Force Microscope**
Tensile Module 1000 N
(Kammrath & Weiss)
Temperature: Room Temperature
Thickness: 10 μ m ... 5 mm



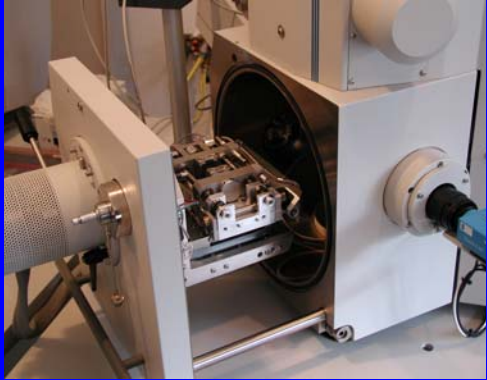

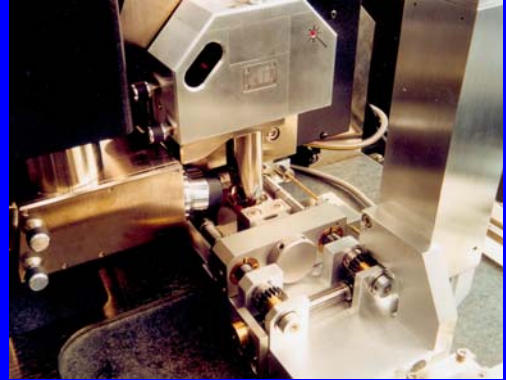
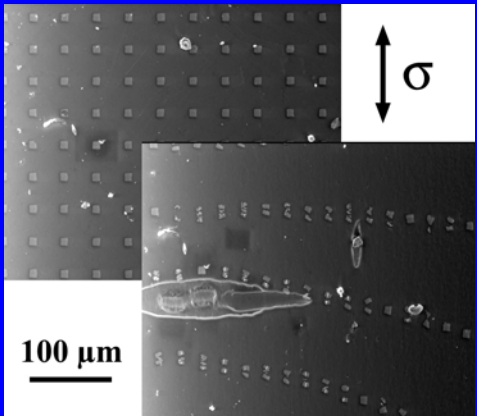
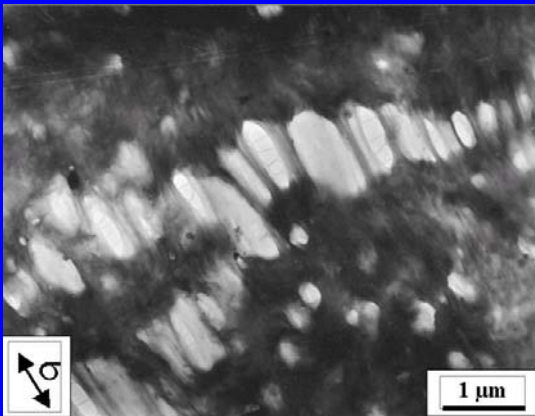
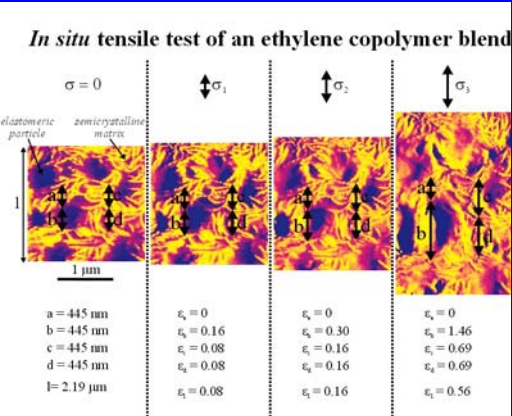
High Voltage Electron Microscope
Tensile Stage (Jeol)
Temperature: Room Temperature
Thickness: 100 nm ... 5 μ m



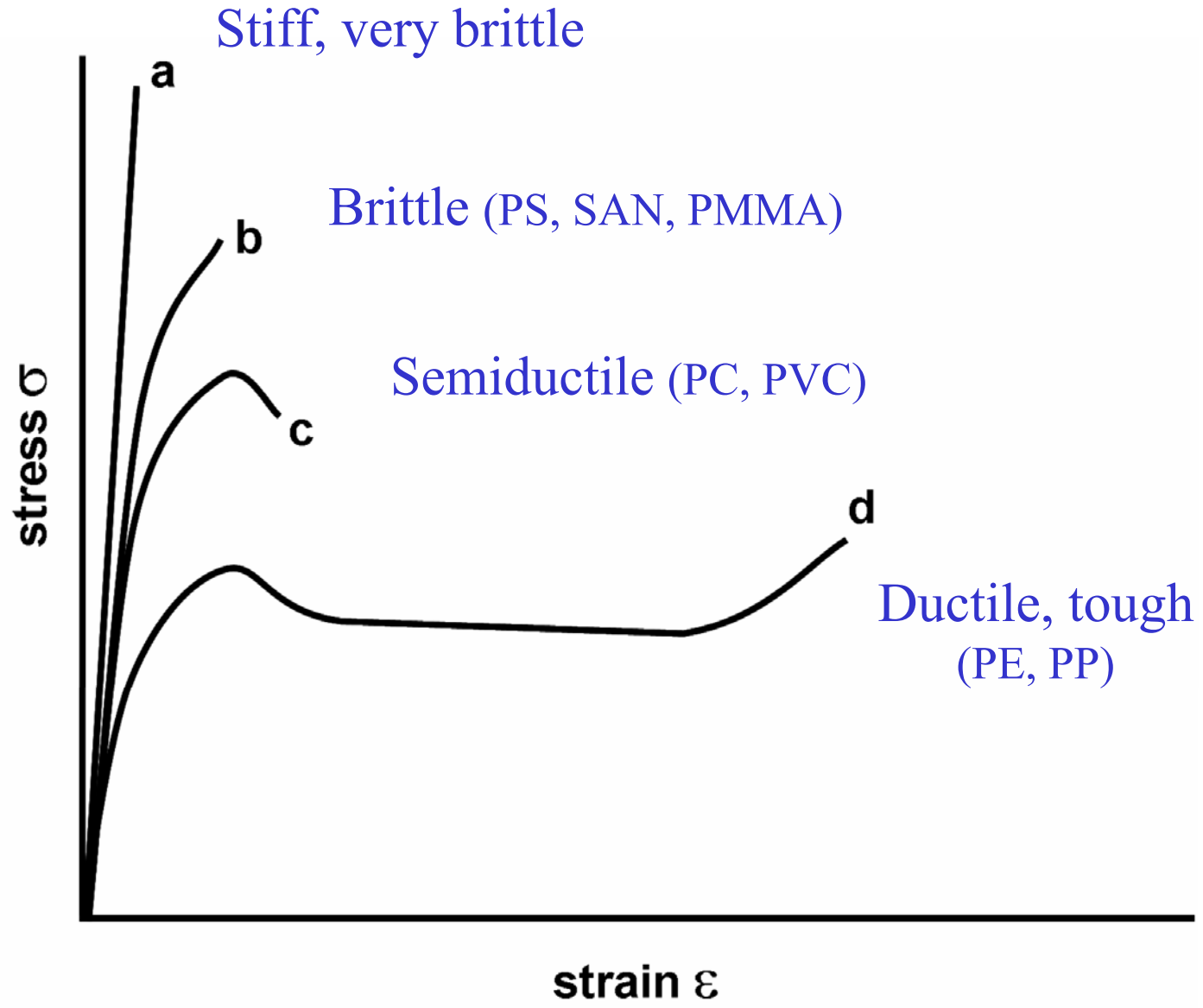
Transmission Electron Microscope
Straining Holder Model 671 (Gatan)
Temperature: -180 °C ... 120 °C
Thickness: 100 nm ... 0.5 μ m

Micromechanical *in situ* Investigations

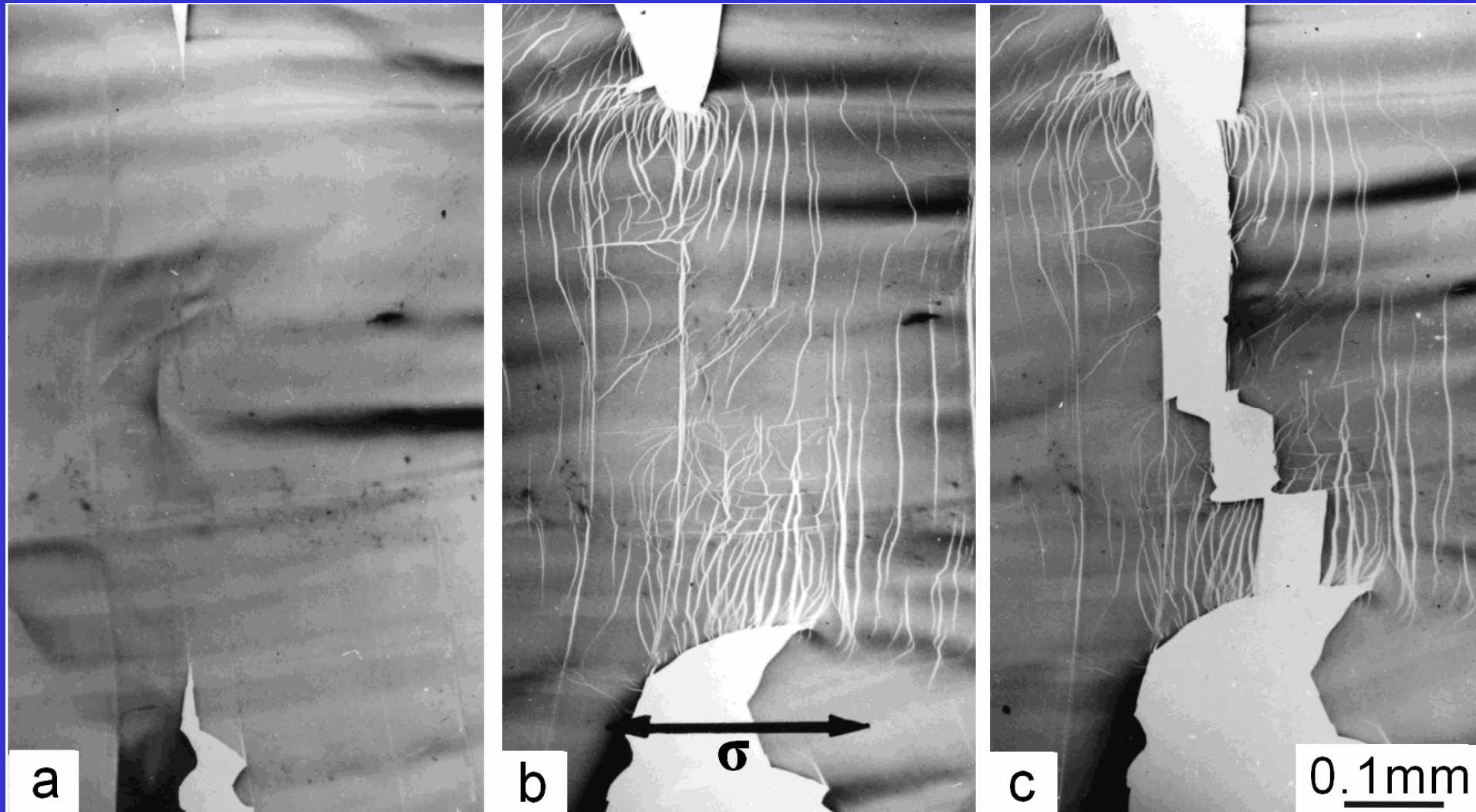
Different Microscopic Techniques (Semicrystalline Polymers)

Method	SEM	TEM	AFM								
Requirements	no evaporation, no etching	no staining	very flat surfaces								
Techniques											
Typical Results	<p data-bbox="92 996 235 1086">Typical Results</p> <p data-bbox="63 1168 266 1320">HDPE/ Copolymer Blends</p> 		<p data-bbox="1387 962 1881 986"><i>In situ</i> tensile test of an ethylene copolymer blend</p>  <table border="1" data-bbox="1387 1239 1881 1350"> <thead> <tr> <th>$\sigma = 0$</th> <th>$\updownarrow \sigma_1$</th> <th>$\updownarrow \sigma_2$</th> <th>$\updownarrow \sigma_3$</th> </tr> </thead> <tbody> <tr> <td> $\epsilon_s = 0$ $\epsilon_t = 0.16$ $\epsilon_c = 0.08$ $\epsilon_d = 0.08$ $\epsilon_s = 0.08$ </td> <td> $\epsilon_s = 0$ $\epsilon_t = 0.30$ $\epsilon_c = 0.16$ $\epsilon_d = 0.16$ $\epsilon_s = 0.16$ </td> <td> $\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.69$ </td> <td> $\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.56$ </td> </tr> </tbody> </table>	$\sigma = 0$	$\updownarrow \sigma_1$	$\updownarrow \sigma_2$	$\updownarrow \sigma_3$	$\epsilon_s = 0$ $\epsilon_t = 0.16$ $\epsilon_c = 0.08$ $\epsilon_d = 0.08$ $\epsilon_s = 0.08$	$\epsilon_s = 0$ $\epsilon_t = 0.30$ $\epsilon_c = 0.16$ $\epsilon_d = 0.16$ $\epsilon_s = 0.16$	$\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.69$	$\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.56$
$\sigma = 0$	$\updownarrow \sigma_1$	$\updownarrow \sigma_2$	$\updownarrow \sigma_3$								
$\epsilon_s = 0$ $\epsilon_t = 0.16$ $\epsilon_c = 0.08$ $\epsilon_d = 0.08$ $\epsilon_s = 0.08$	$\epsilon_s = 0$ $\epsilon_t = 0.30$ $\epsilon_c = 0.16$ $\epsilon_d = 0.16$ $\epsilon_s = 0.16$	$\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.69$	$\epsilon_s = 0$ $\epsilon_t = 1.46$ $\epsilon_c = 0.69$ $\epsilon_d = 0.69$ $\epsilon_s = 0.56$								

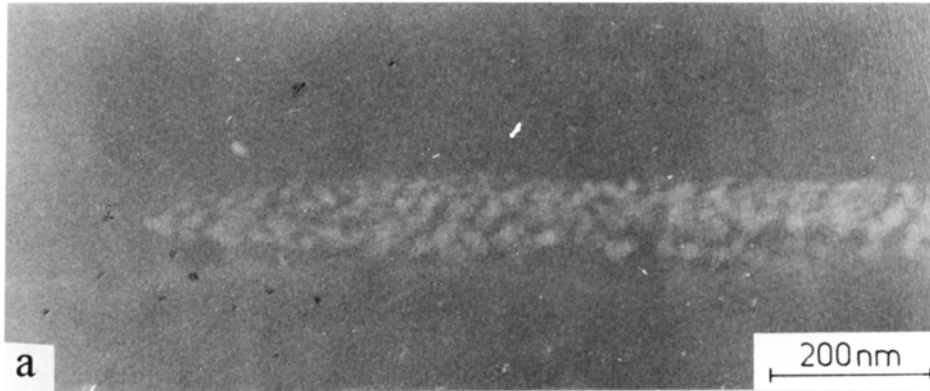
Examples



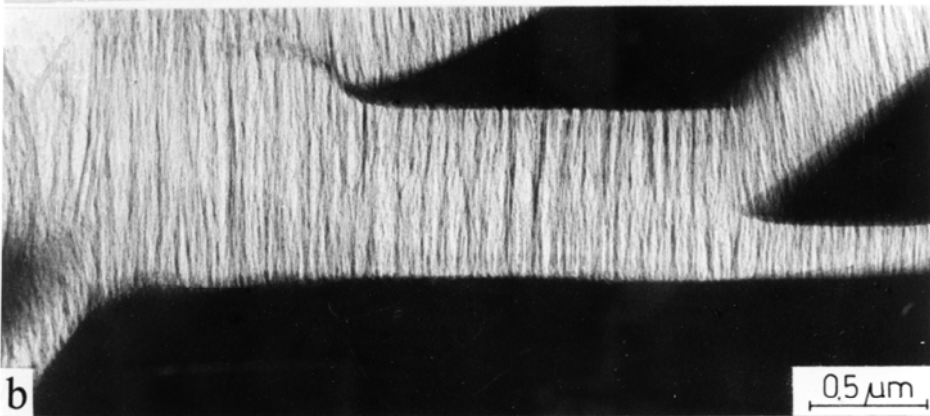
In situ deformation of PS in HVTEM



Craze in PS



a) Pre-craze

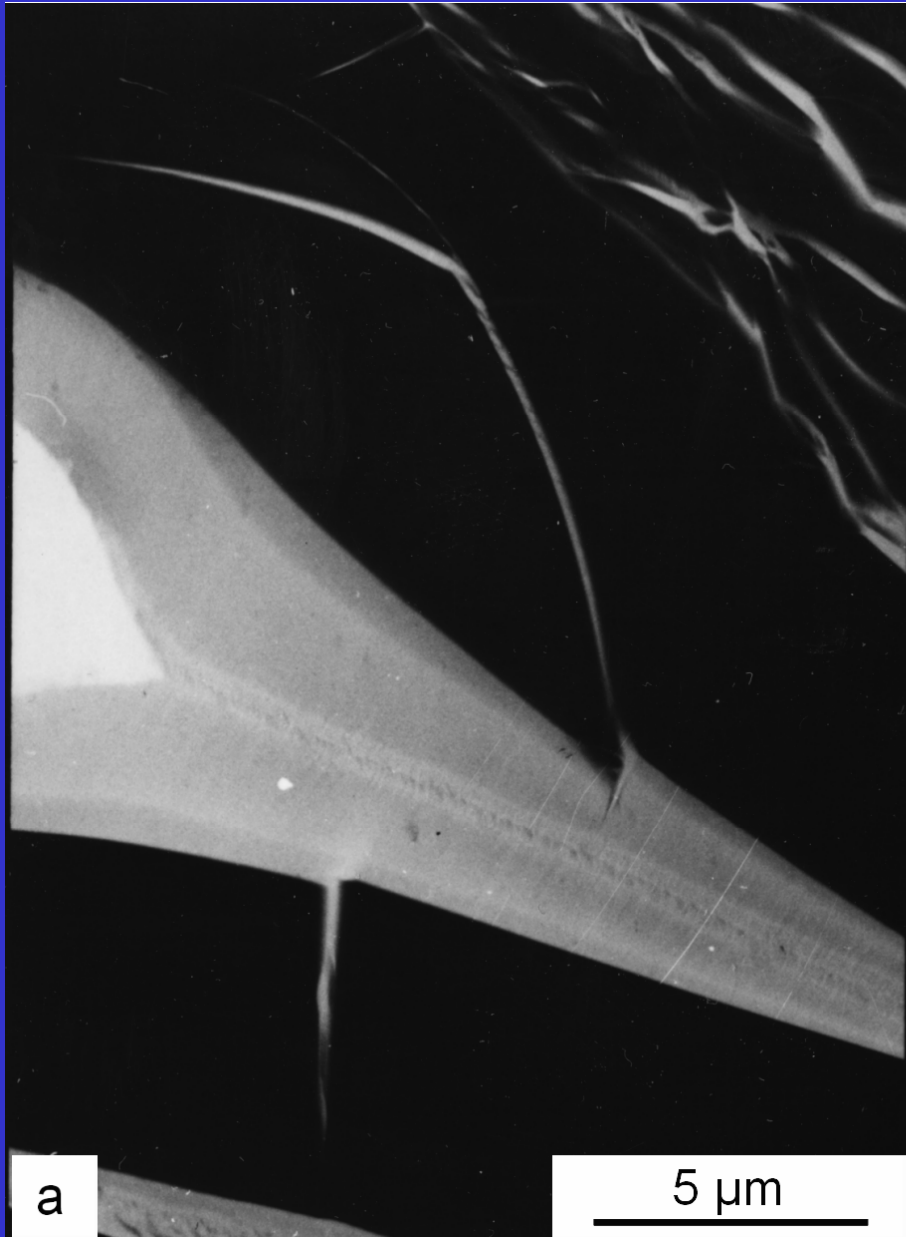


b) Fibrillated craze

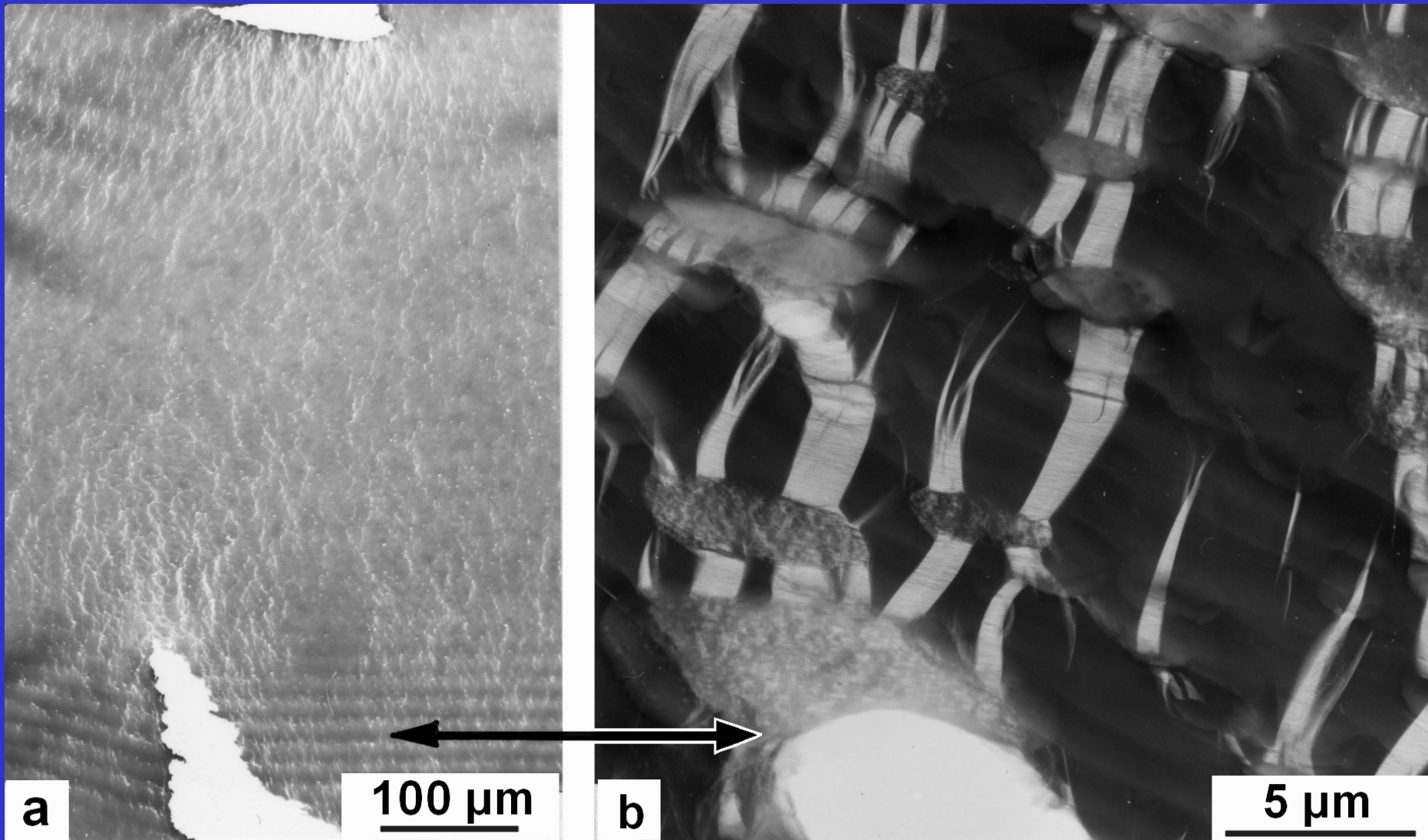


c) Laser-light
diffraction pattern

Craze rupture in PS (HVTEM)



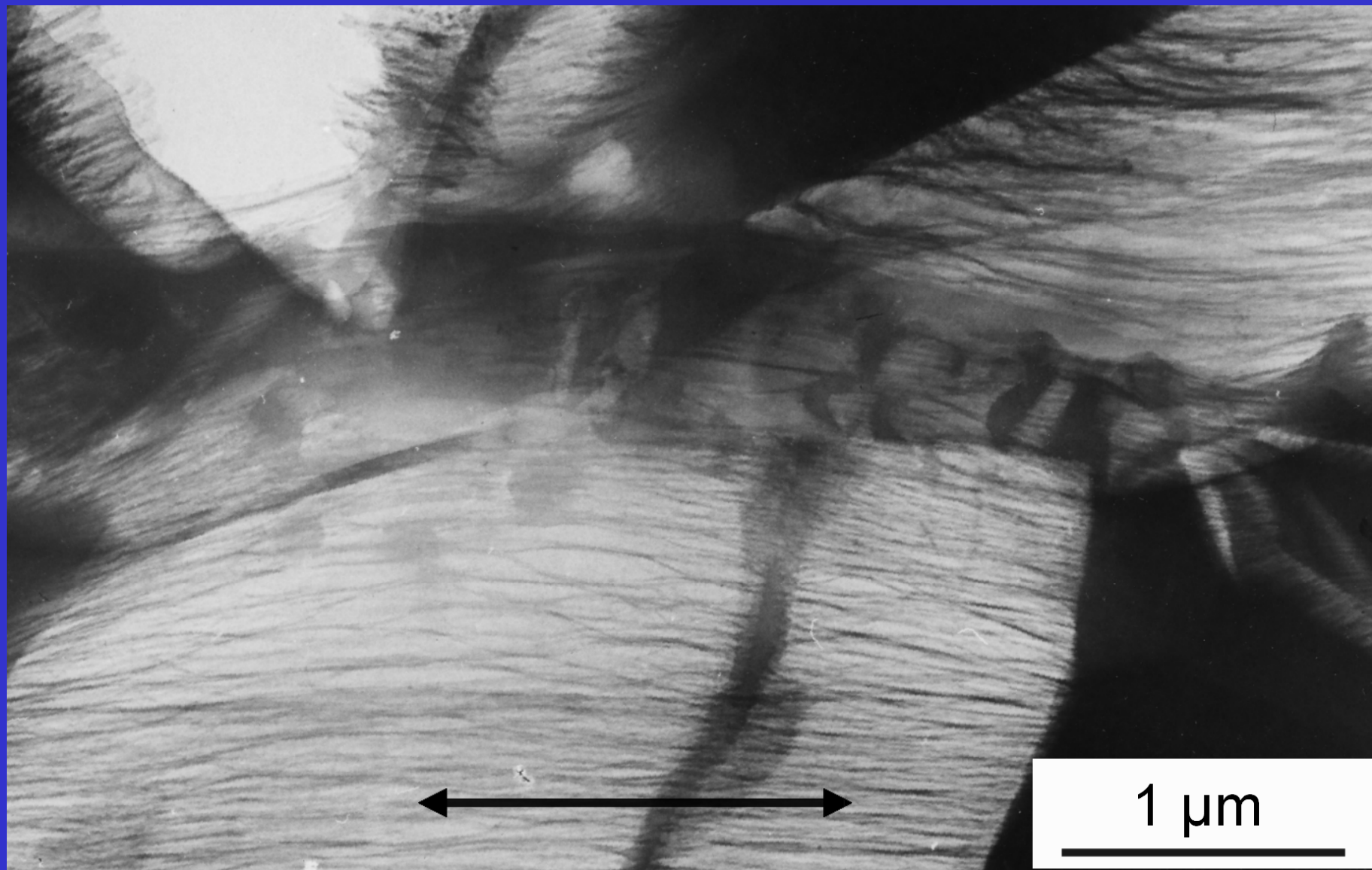
Rubber-toughened Polymer (HIPS)



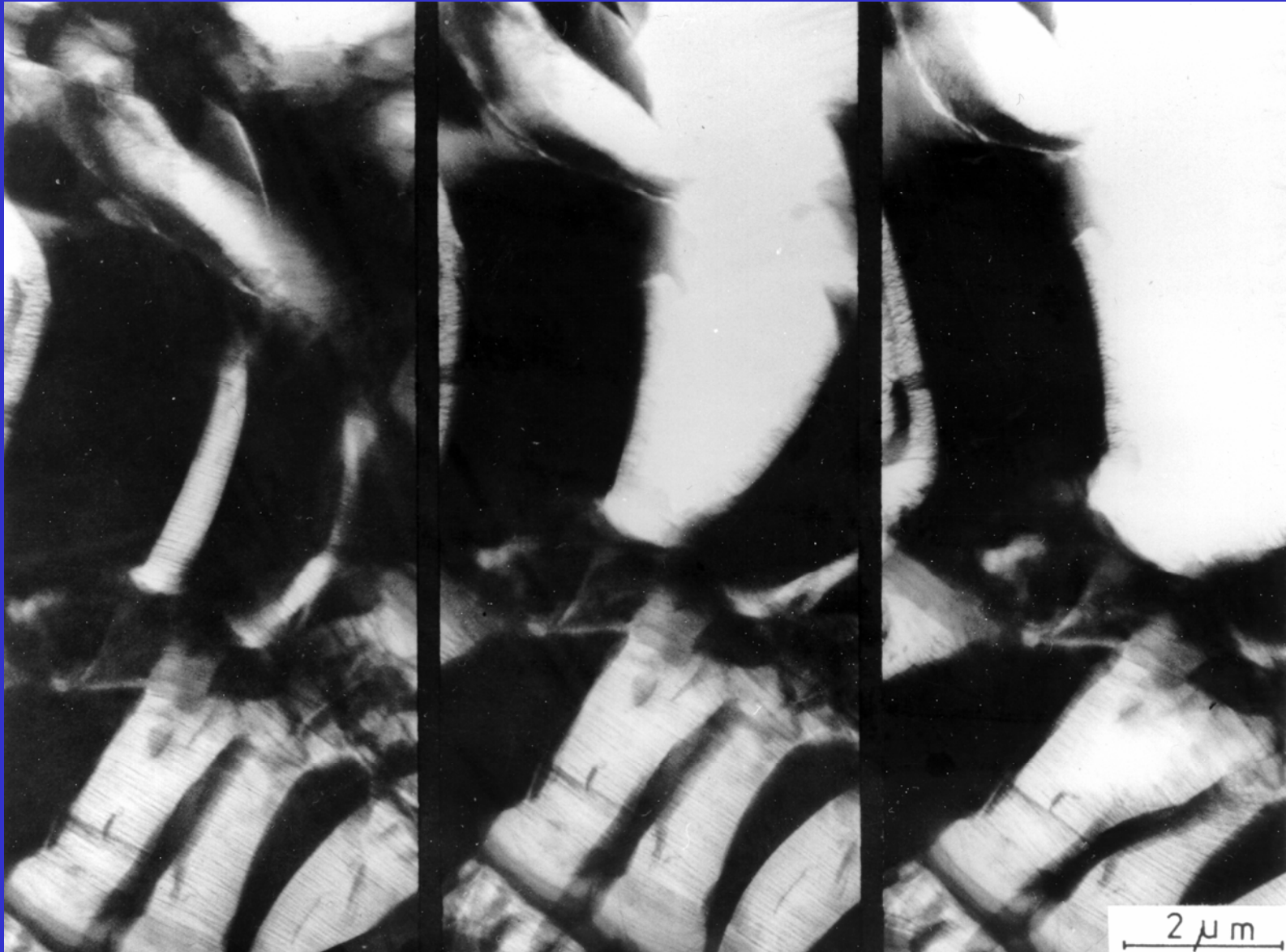
Rubber-toughened Polymer (HIPS)



Rubber-toughened Polymer (HIPS)

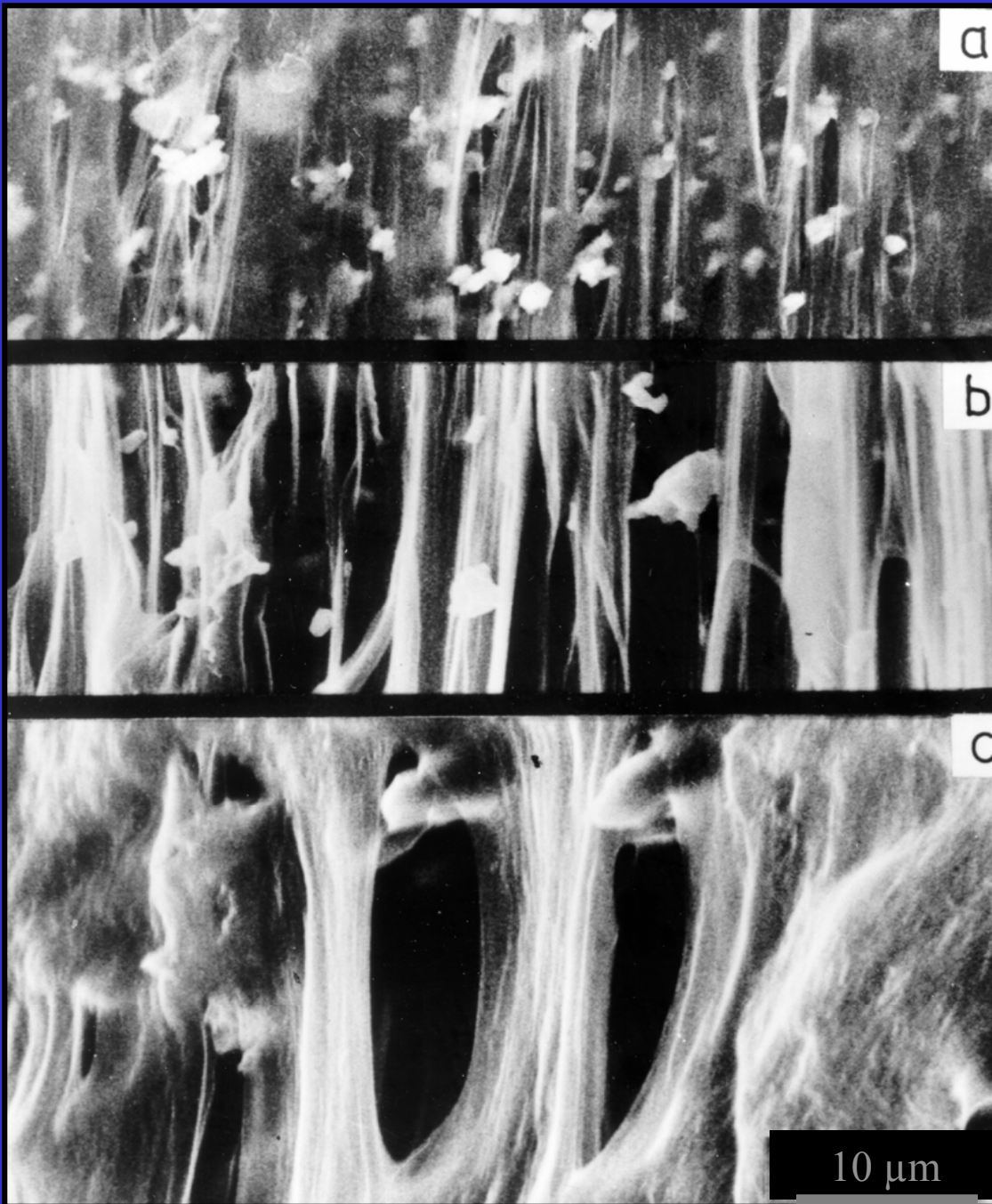


Rubber-toughened Polymer (HIPS)



In-situ crack propagation in HIPS

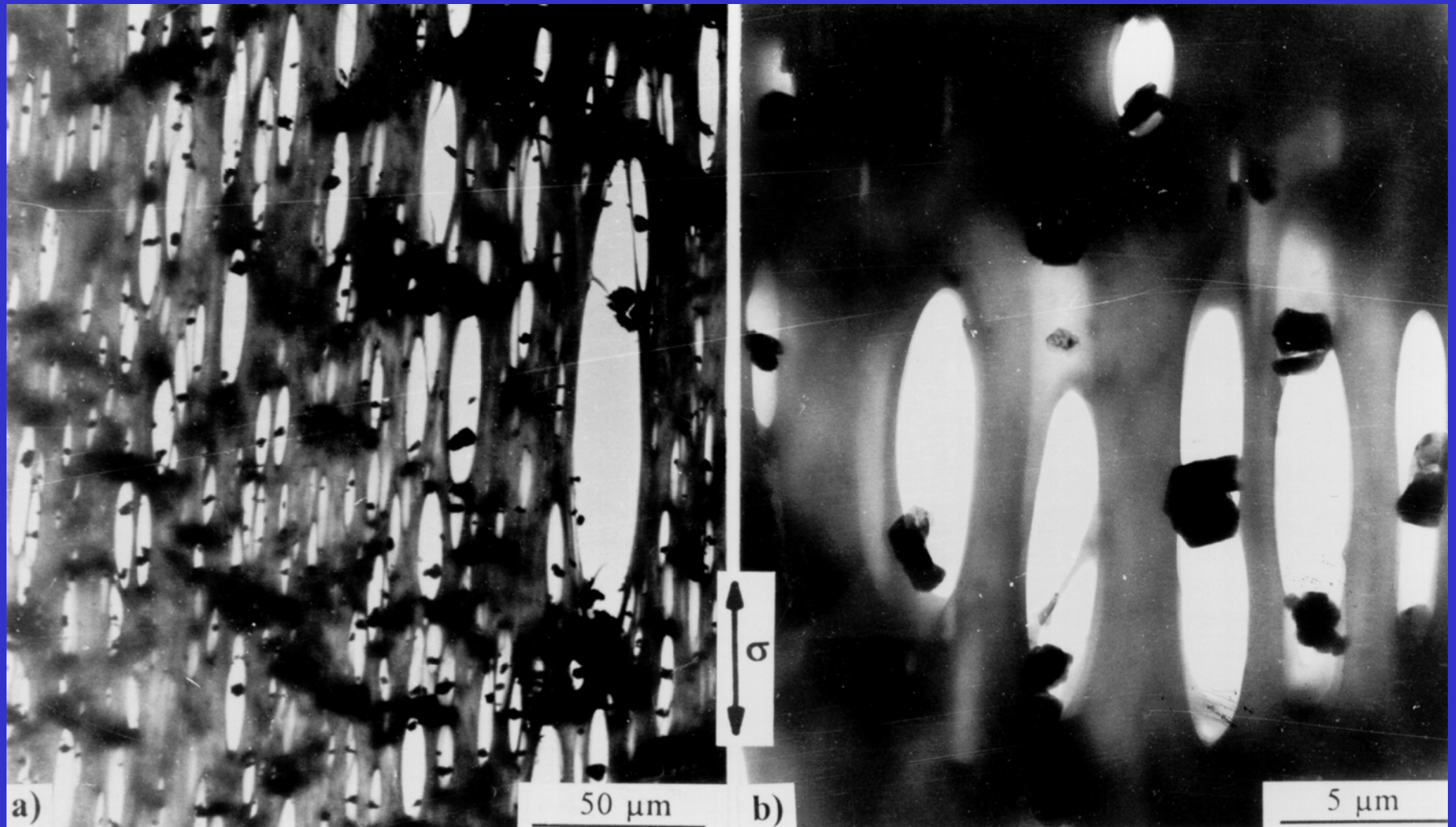
PE Composite



Dependence of
void size and fibril
thickness on
particle diameter in
filled HDPE:

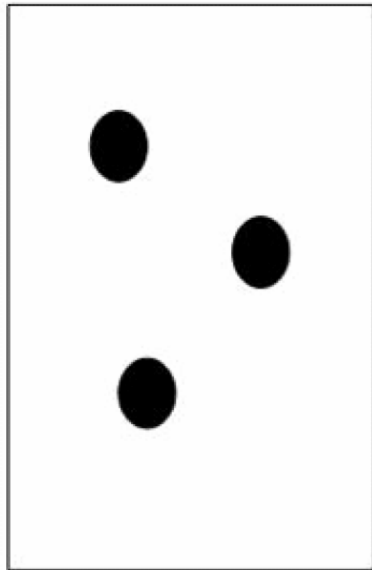
- a) 1 μm
- b) 3 μm
- c) 8 μm

Deformation structures of particle-filled PP (10 wt.% Al(OH)₃)



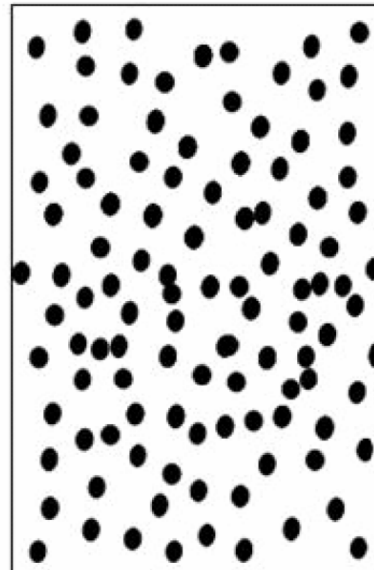
Micro- and Nanocomposites

3 Vol. %



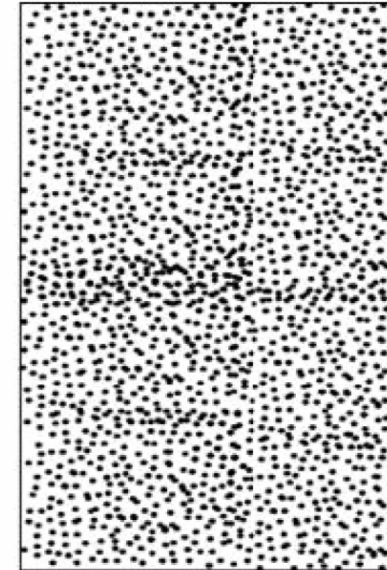
10 μm

3



1 μm

3000



100 nm

3 000 000

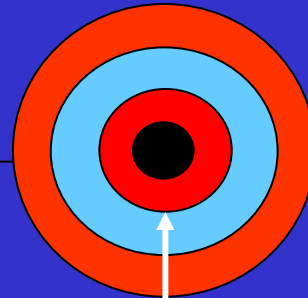
Effect of Nanoparticle

Influence of Interface

1 μm

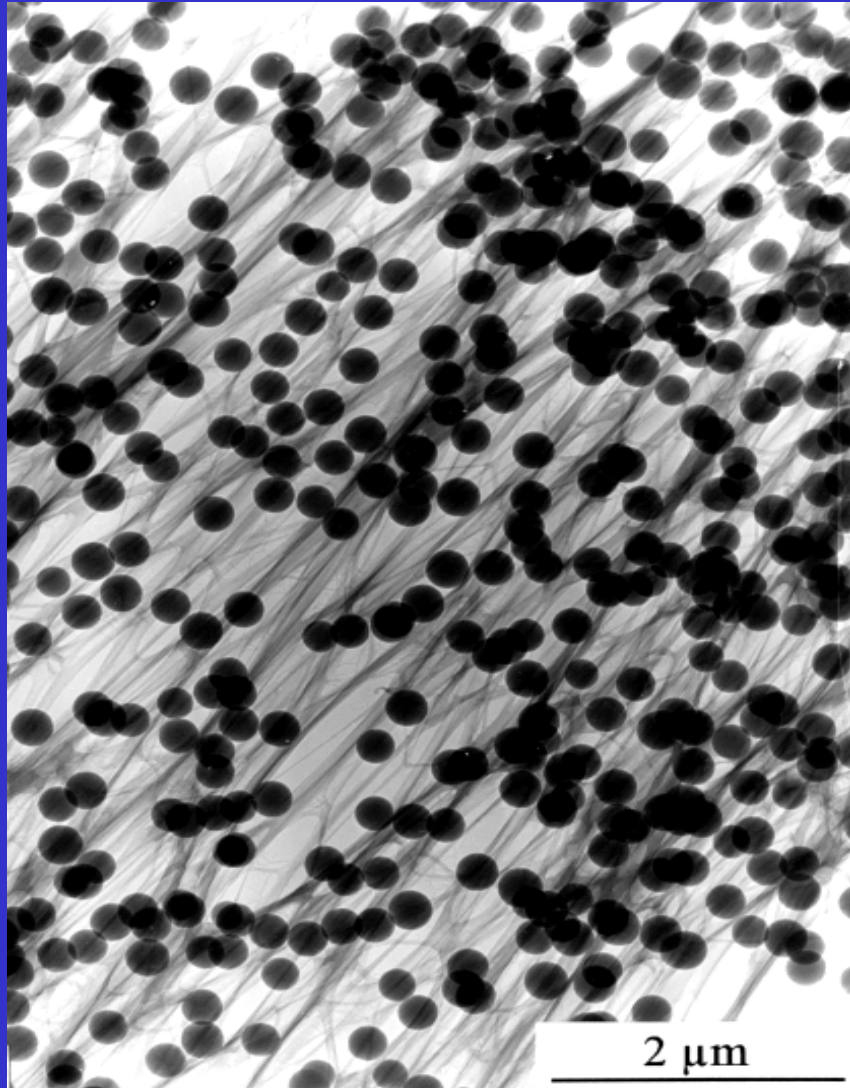
100 nm

10 nm

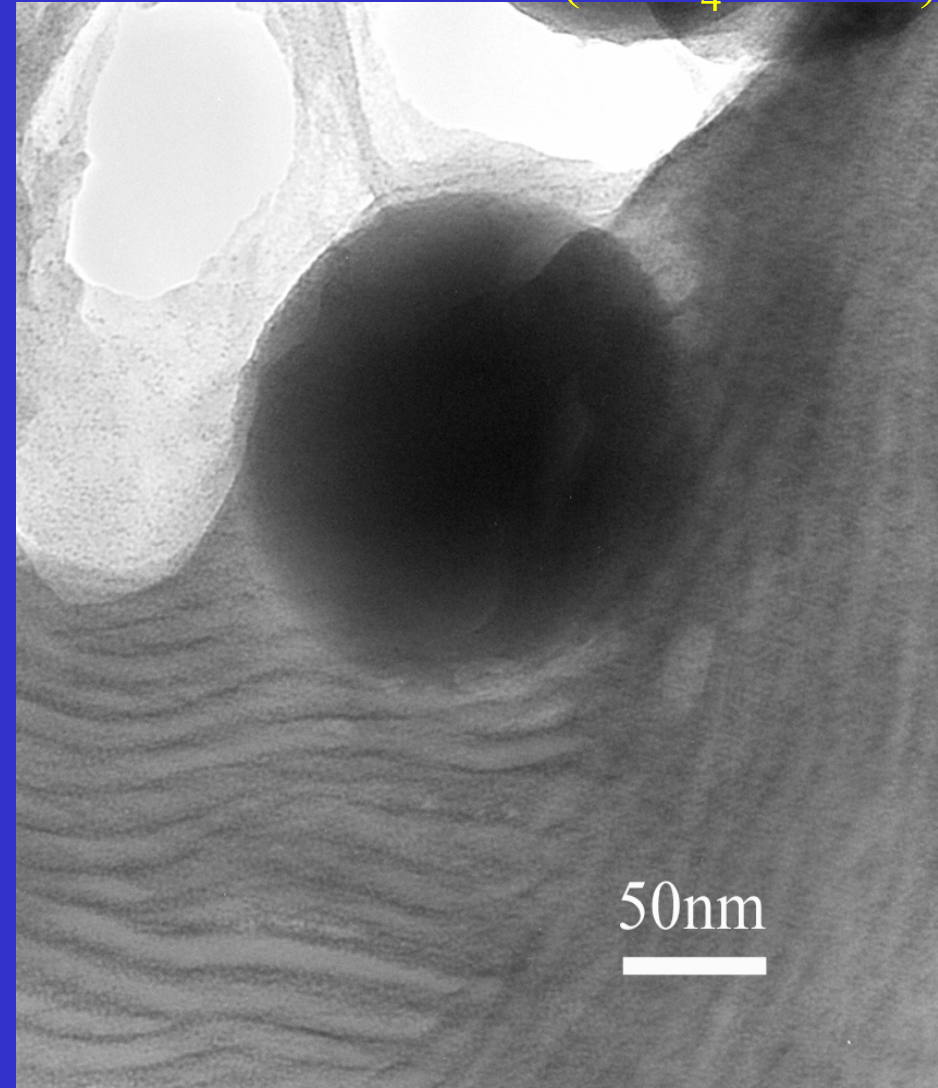


Deformation structures of particle-filled PE (10 wt.% SiO₂)

HVEM

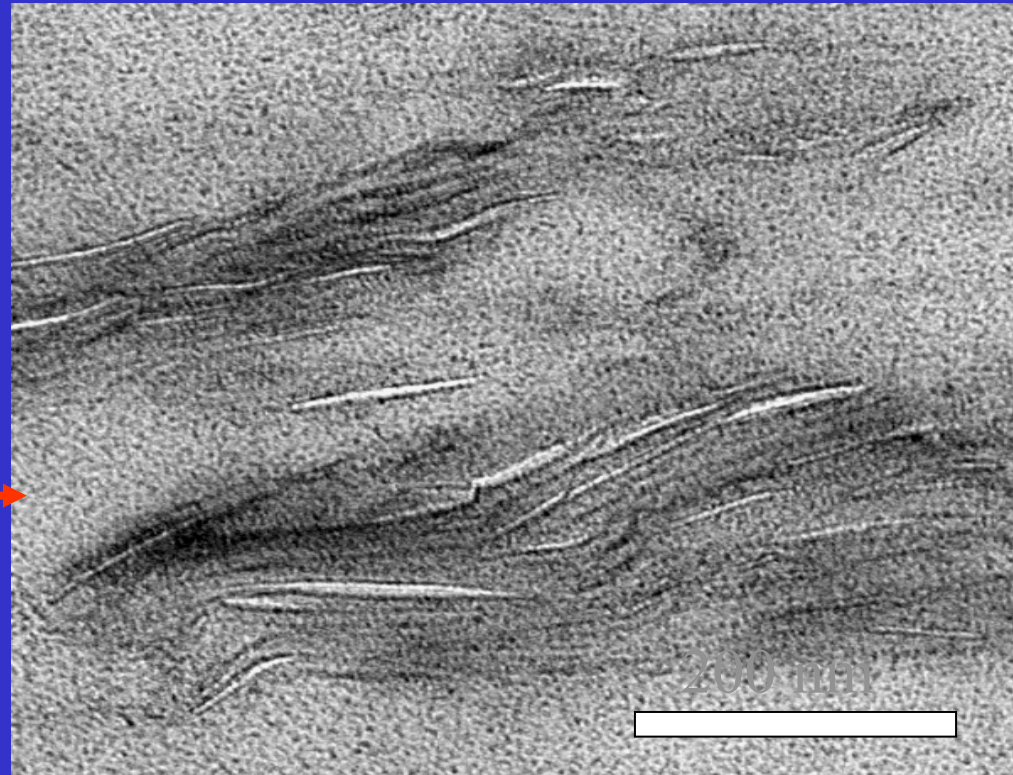


TEM (RuO₄ stained)

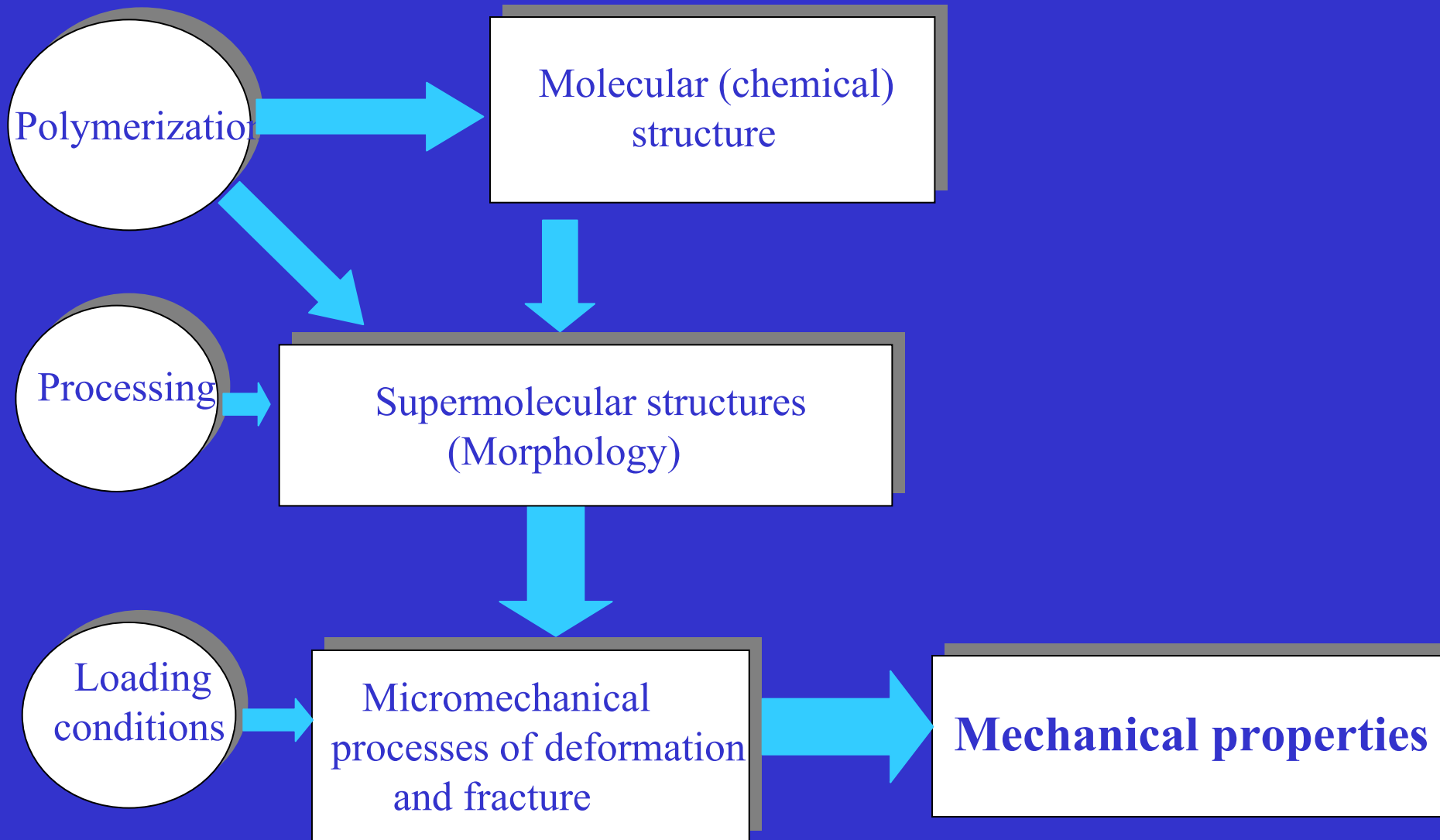


PP-Clay-Nanocomposite

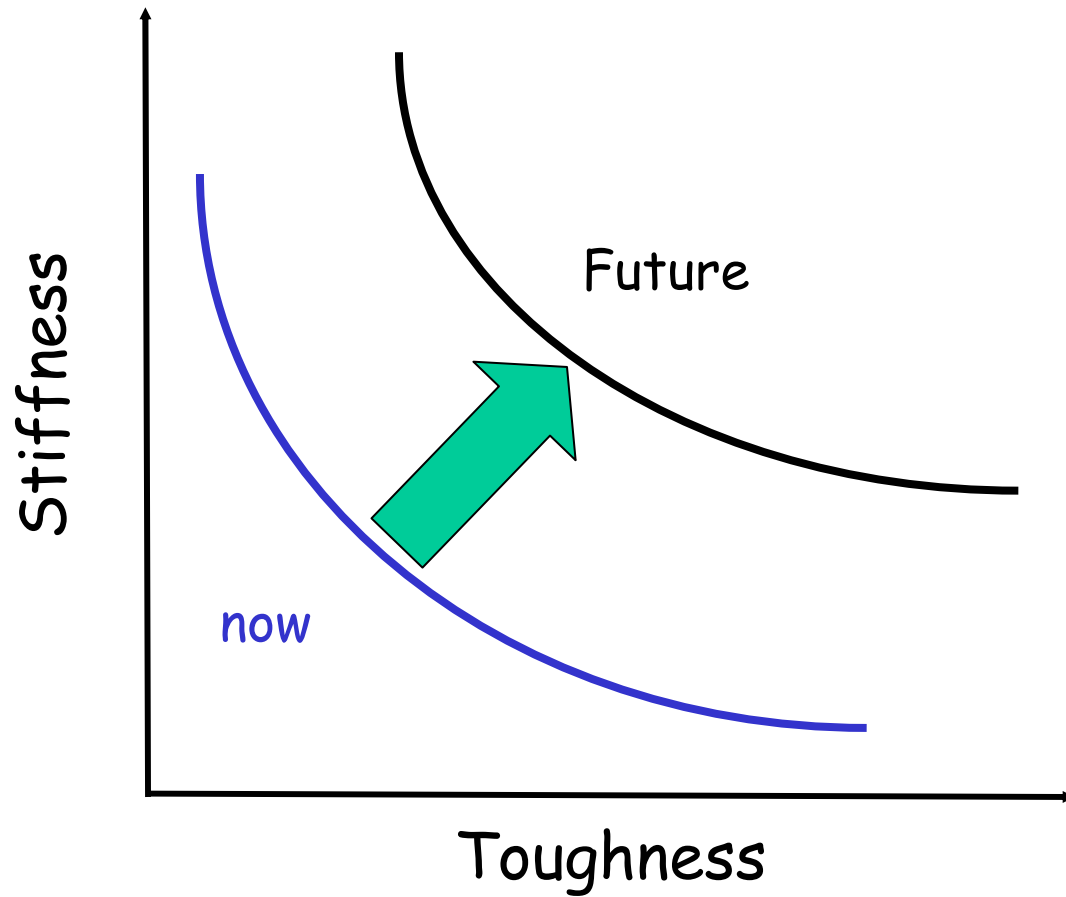
Deformation structure



RESULT of EM: *Better Correlations*



RESULT of EM: *Better Properties*





SPRINGER LABORATORY

Michler



SPRINGER LABORATORY

G. H. Michler

Electron Microscopy of Polymers

There are many books on electron microscopy, however, the study of polymers using EM necessitates special techniques, precautions and preparation methods, including ultramicrotomy. This book discusses the general characteristics of the various techniques of EM, including scanning force microscopy (AFM). The application of these techniques to the study of morphology and properties, particularly micromechanical properties, is described in detail. Examples from all classes of polymers are presented.



Electron Microscopy of Polymers

G. H. Michler

Electron Microscopy of Polymers

ISBN 978-3-540-36350-7



springer.com

 Springer

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5. Atomic Force Microscopy

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- 12. Preparation for (in situ) Deformation Tests**
- 13. Contrast Enhancement**

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